

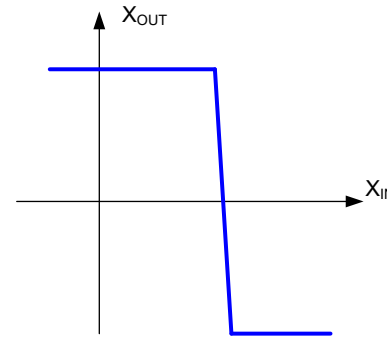
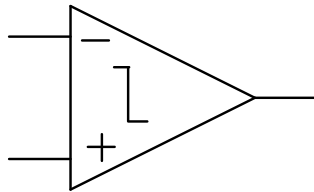
EE 435

Lecture 37

ADC Design

Analog to Digital Converters

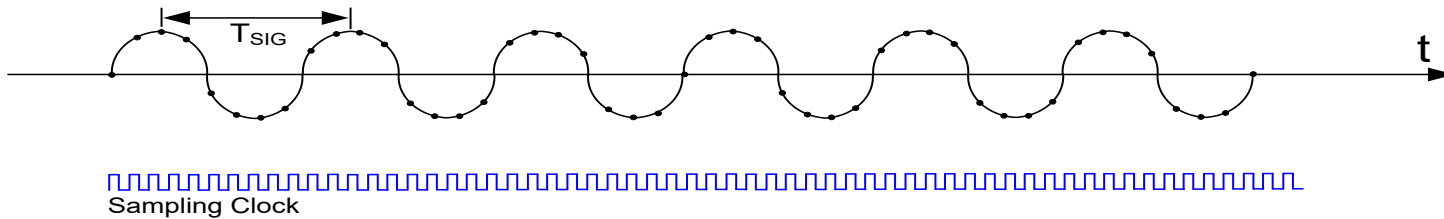
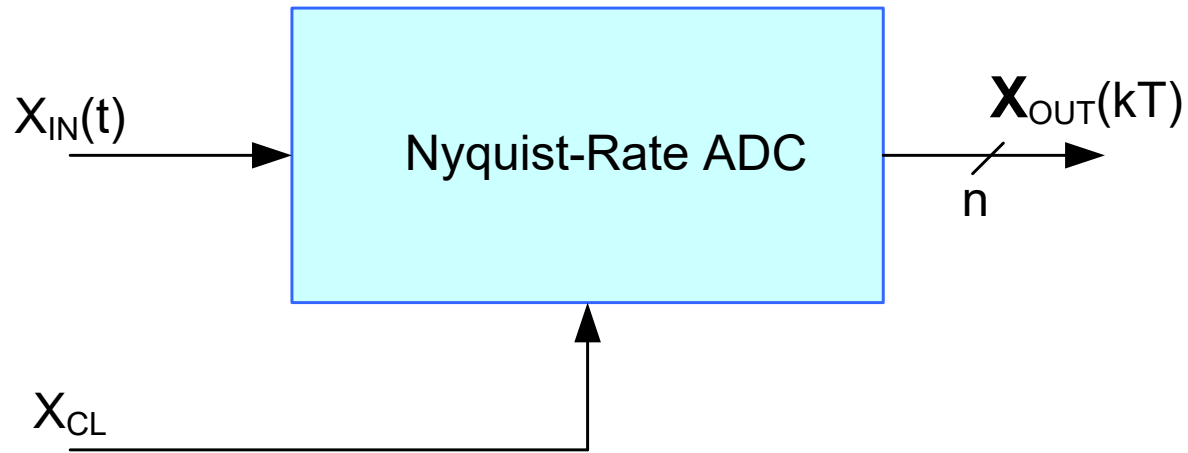
The conversion from analog to digital in most ADCs is done with comparators



ADC design is primarily involved with designing comparators and embedding these into circuits that are robust to nonideal effects

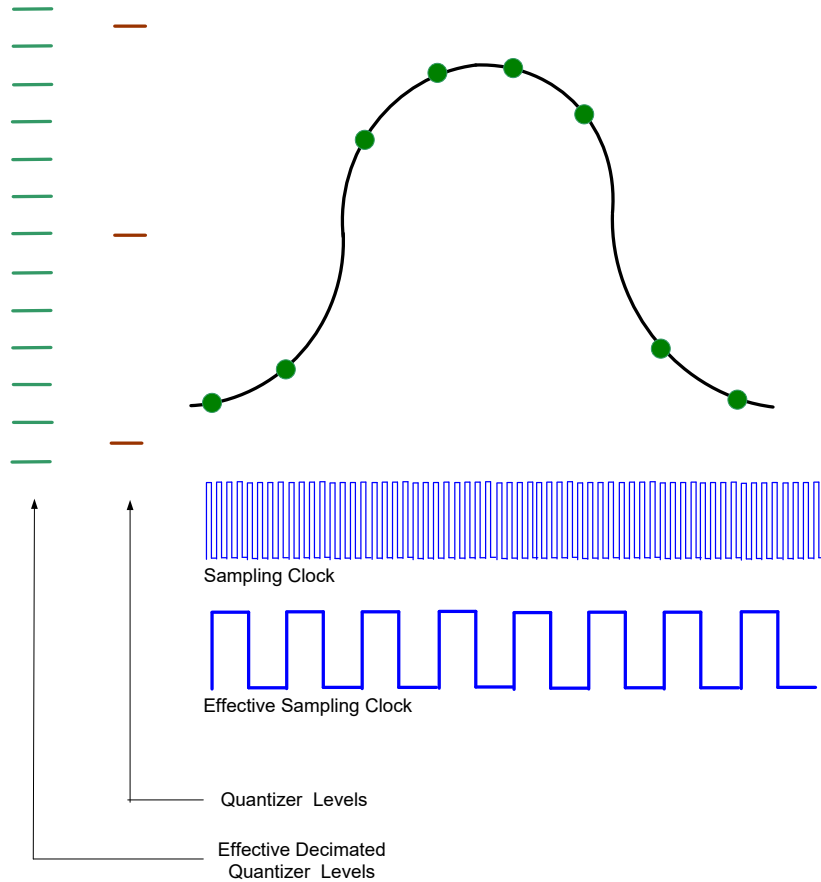
Review from Last Lecture

Nyquist Rate



Review from Last Lecture

Over-Sampled



Over-sampling ratios of 128:1 or 64:1 are common
Dramatic reduction in quantization noise effects
Limited to relatively low frequencies

ADC Types

Nyquist Rate

- Flash
- Pipeline
- Two-Step Flash
- Multi-Step Flash
- Cyclic (algorithmic)
- Successive Approximation
- Folded
- Dual Slope

Over-Sampled

- Single-bit
- Multi-bit
- First-order
- Higher-order
- Continuous-time

Review from Last Lecture

ADC Types

Nyquist Rate

- Flash
- Pipeline
- Two-Step Flash
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- Cyclic (algorithmic)
- Interpolating
- Successive Approximation
- Folded
- Dual Slope

Over-Sampled

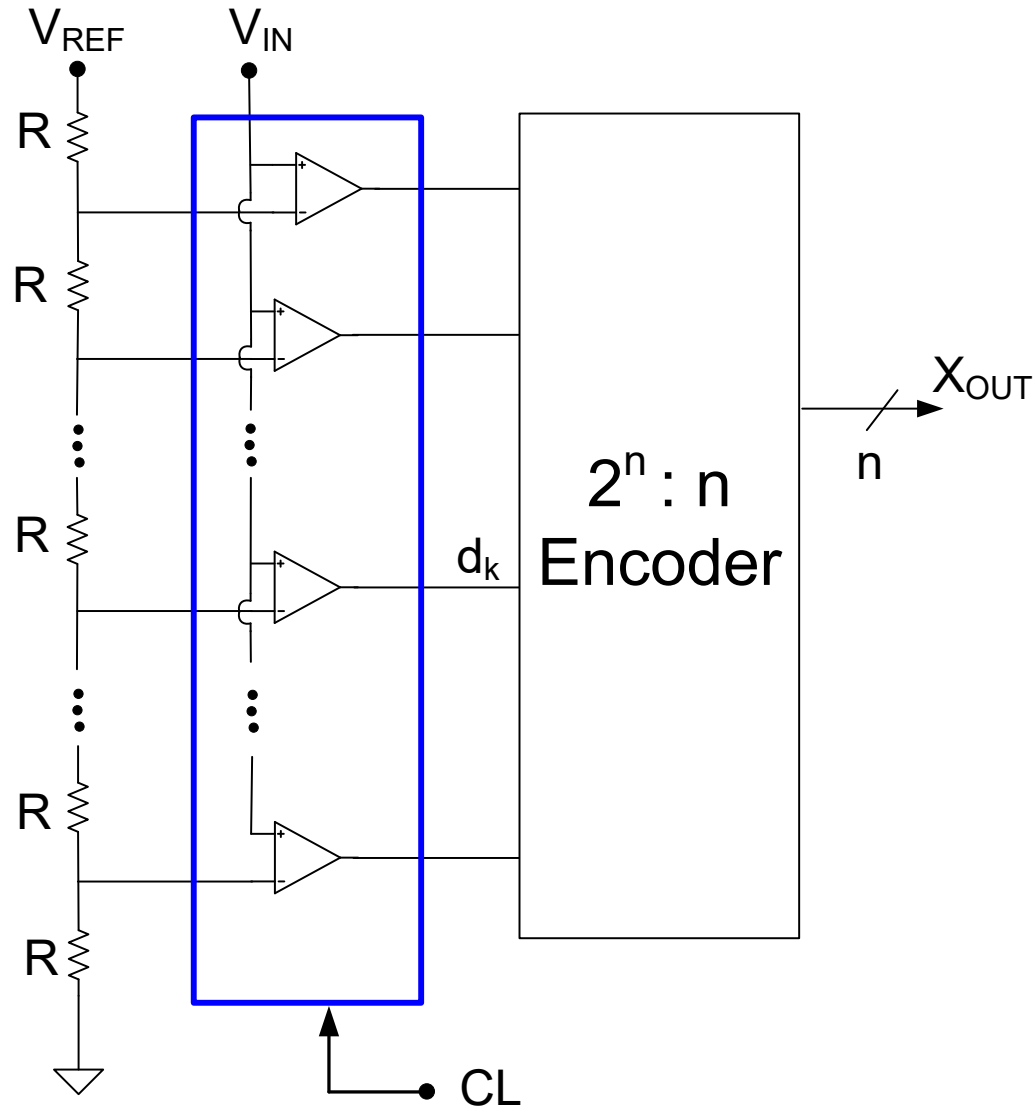
- Single-bit
- Multi-bit
- First-order
- Higher-order
- Continuous-time

All have comparable conversion rates

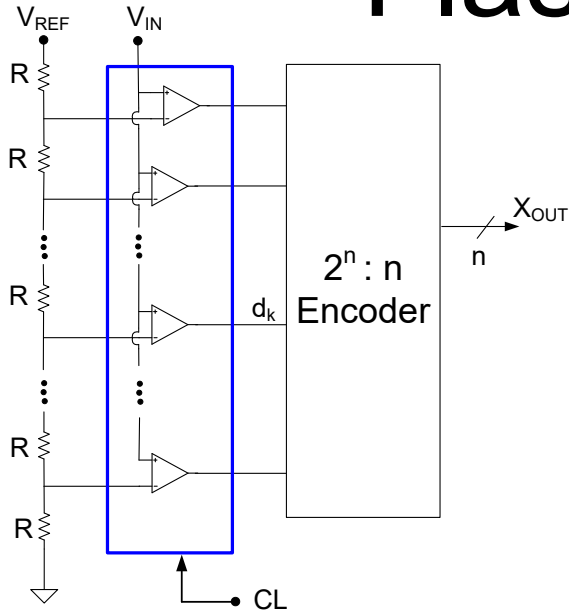
Basic approach in all is very similar

Review from Last Lecture

Flash ADC



Flash ADC



Asynchronous operation (benefit or liability?)

Vulnerable to missing codes

High number of comparators needed

R-string area requires considerable area and source of INL limitations

Offset voltage of comparators of concern

Simultaneous switching of large number of comparators can cause supply glitches

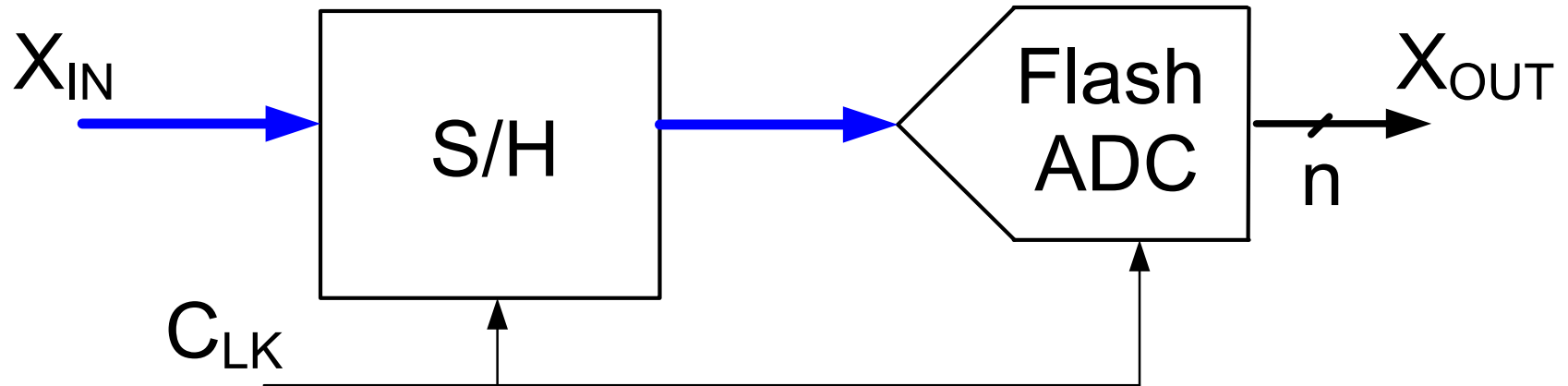
Large parasitic capacitance on V_{IN} pin

Bubbles in output can occur

Metastability an issue

Power dissipation can be large

Flash ADC with Front-End S/H



Prevents input to ADC from changing during sampling (Synchronous instead of Asynchronous)

Performance of ADC can be no better than that of the S/H

Significant amount of effort and power may go into the S/H

Comparators

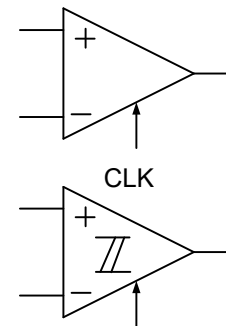
High-Gain Saturating Amplifier



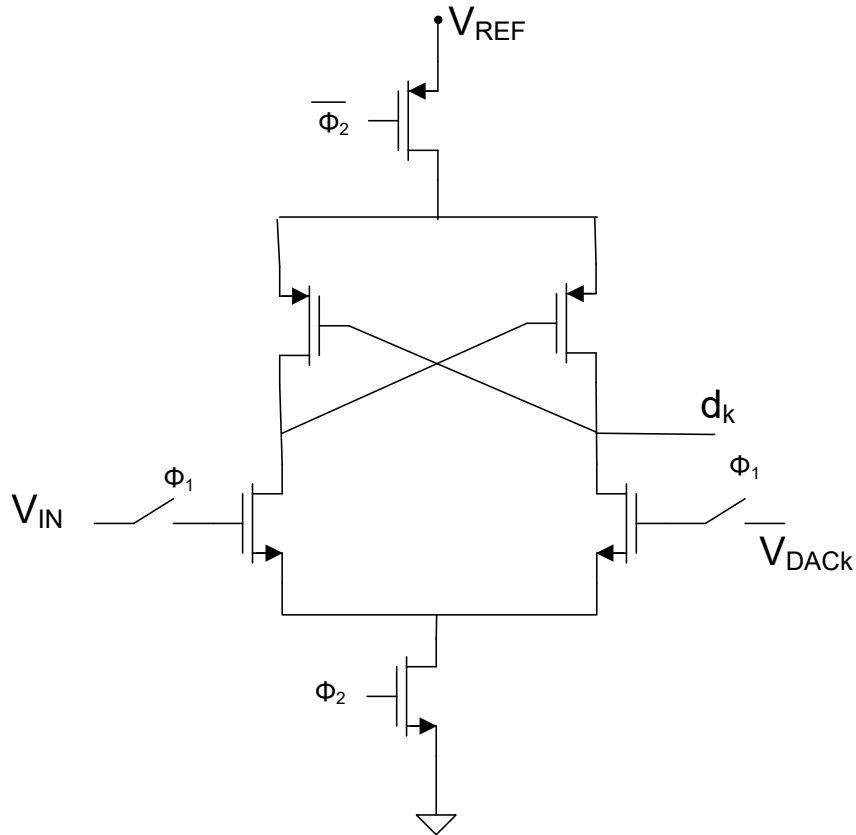
Clocked Comparator

Linear High-gain Amplifier

Regenerative Feedback Amplifier

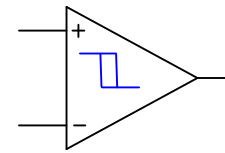


Clocked Comparator

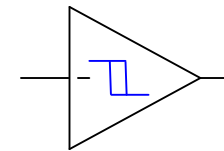


Regenerative Feedback

Regenerative Comparators



Differential



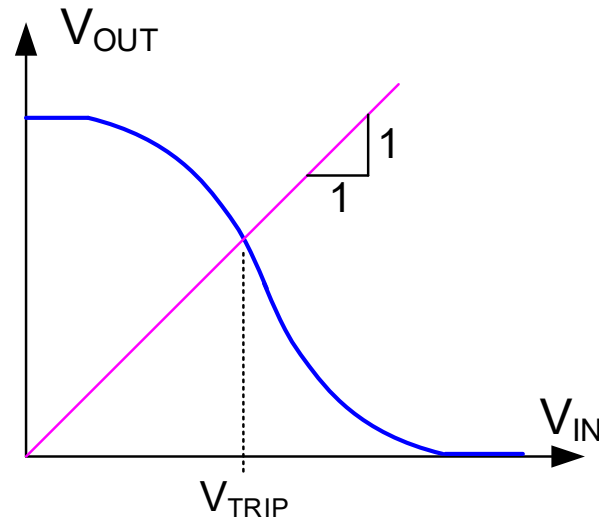
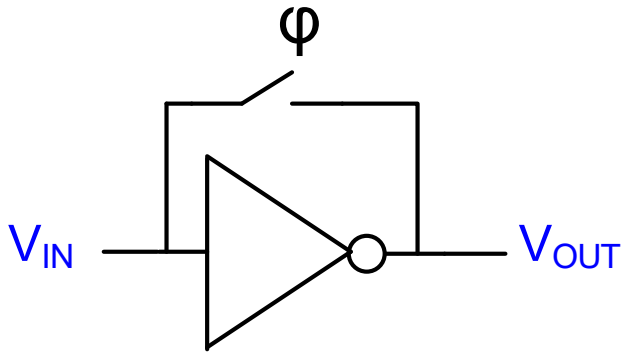
Single-Ended

Large offset voltage (100mV or more)

Previous-decision affects offset

Clocked Comparator

Recall:

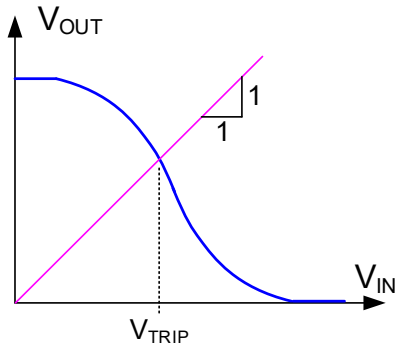
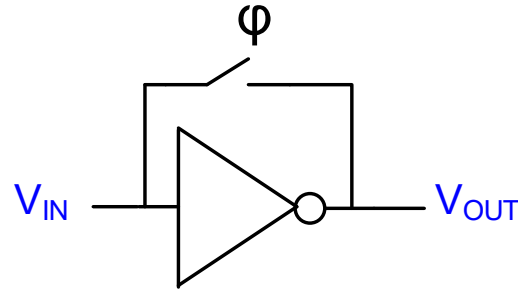


Forcing $V_{OUT} = V_{IN}$ (by closing switch ϕ) forces the amplifier to operate at the trip point

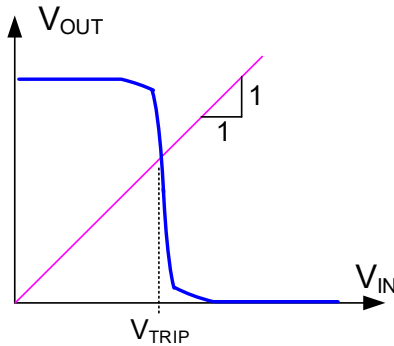
Concept applicable irrespective of how large the gain of the amplifier is

But power dissipation may be high when ϕ is activated

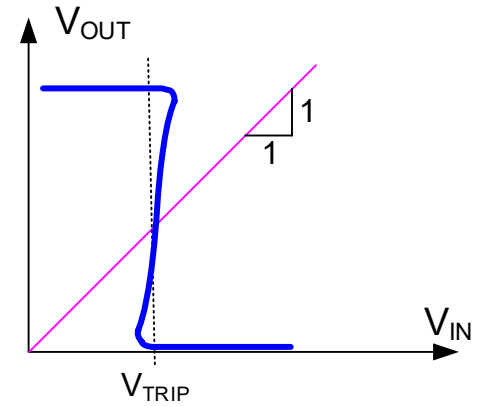
Clocked Comparator



Low Gain Comparator

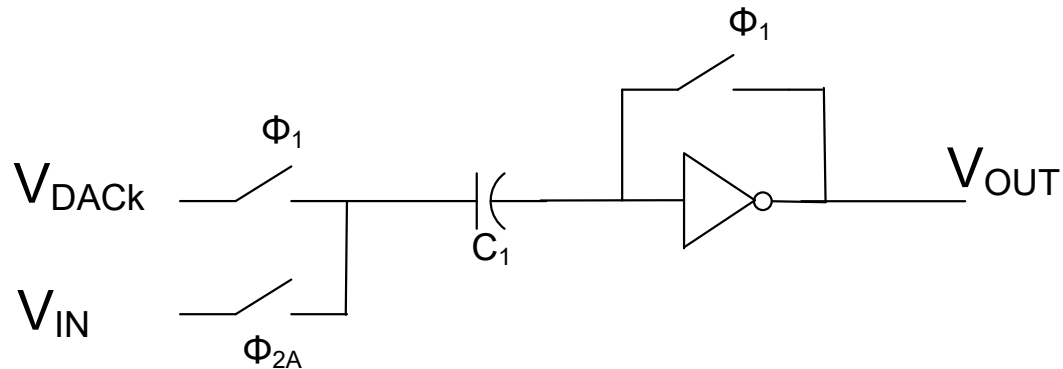


High Gain Comparator



High Gain Comparator with hysteresis (regenerative)

Clocked Comparator



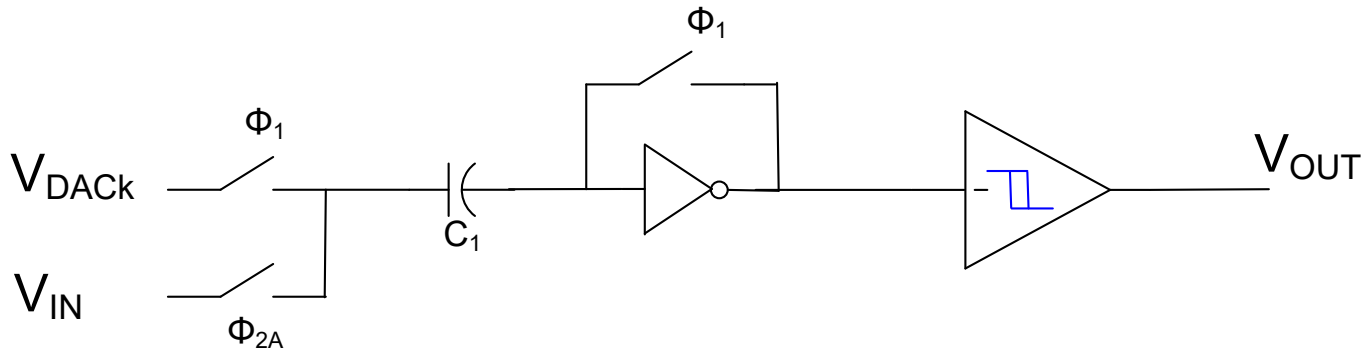
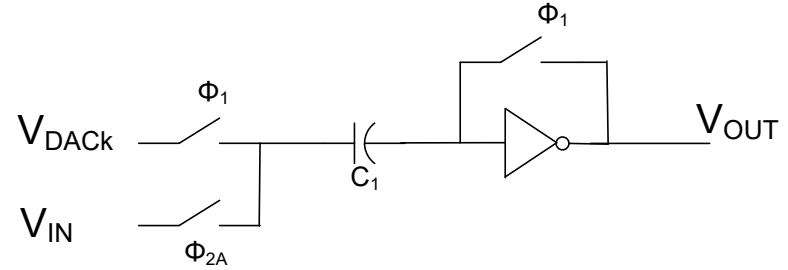
Preamplifier with offset compensation

Ideally removes all offset effects

May not have a large enough gain

Regenerative latch often used

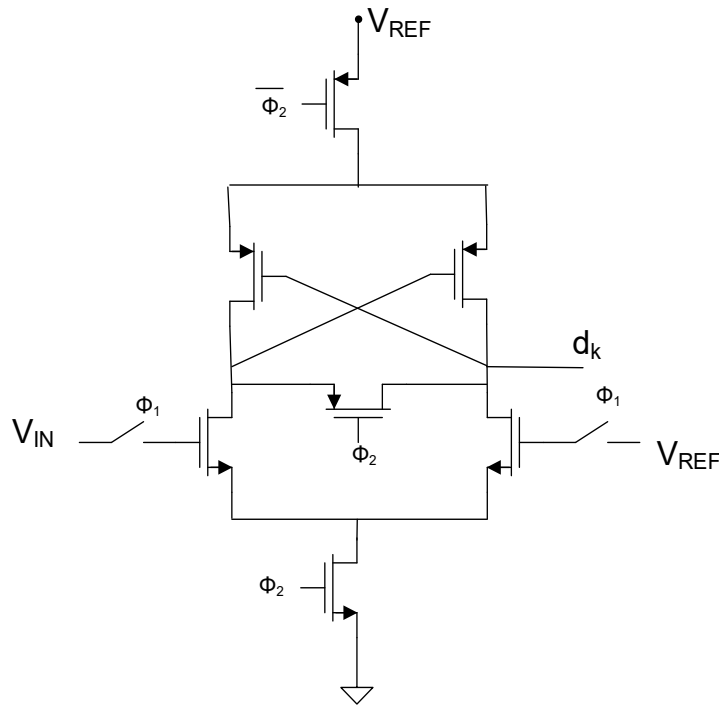
Clocked Comparator



Preamplifier with offset compensation and regenerative latch

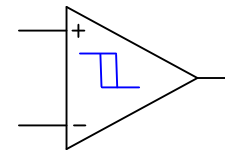
Gain of preamplifier may still not be large enough

Clocked Comparator with Regenerative Feedback

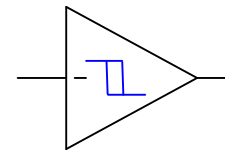


Regenerative Feedback

Regenerative Comparators



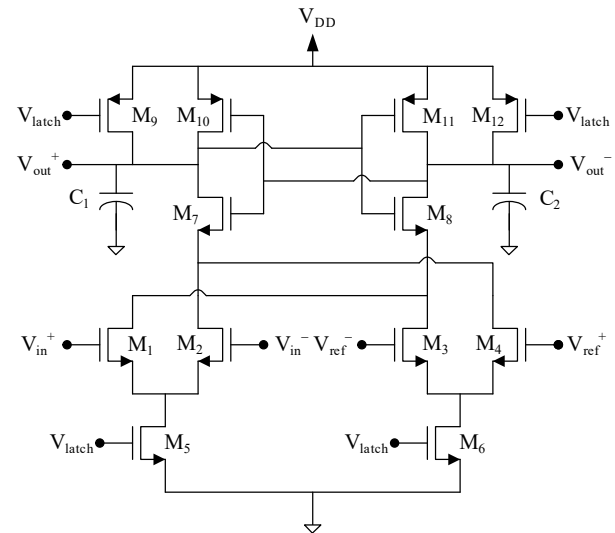
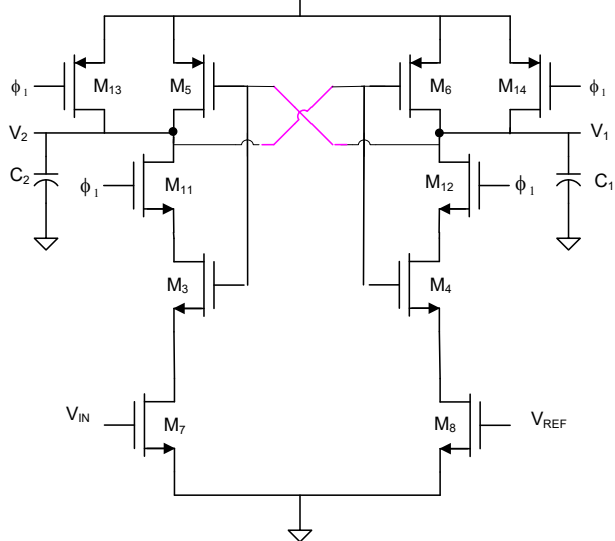
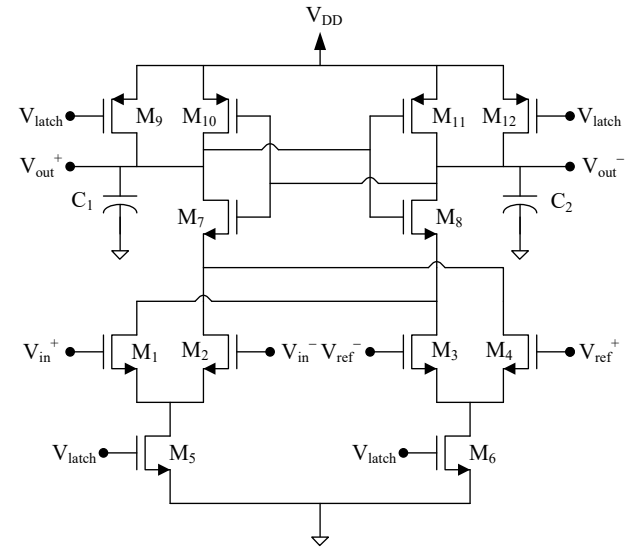
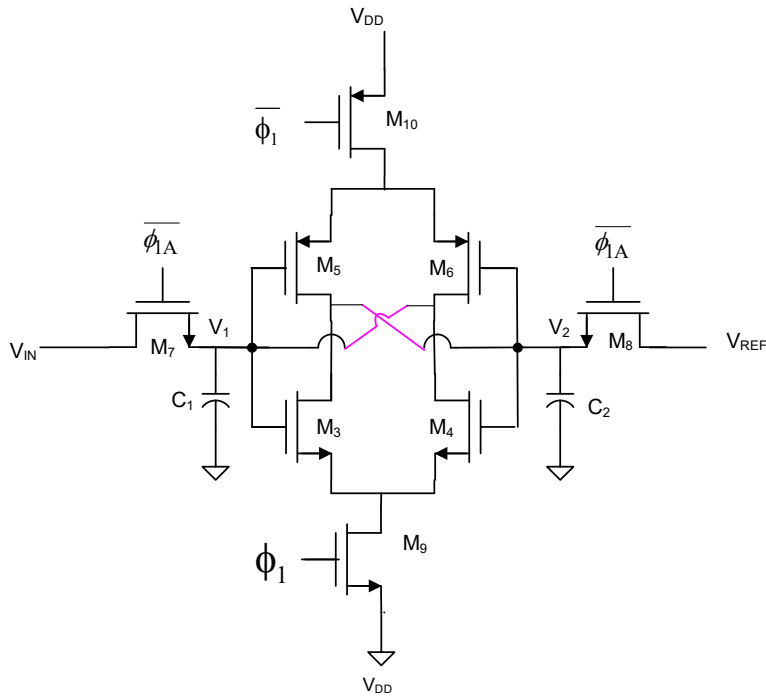
Differential



Single-Ended

- Regenerative feedback often used to force decision when differential inputs are small
- Several variants of clocked comparators are available
- Important to not have trip point dependent upon previous comparison results
- Often one or more linear gain stages precede the regenerative stage
- Power dissipation can be small in regenerative feedback comparators
- Large offset voltage (100mV or more) common for regenerative feedback comparators

Clocked Comparator with Regenerative Feedback



Flash ADC Summary

Flash ADC

Very fast

Simple structure

Usually Clocked

Bubble Removal Important

Seldom over 6 or 7 bits of resolution

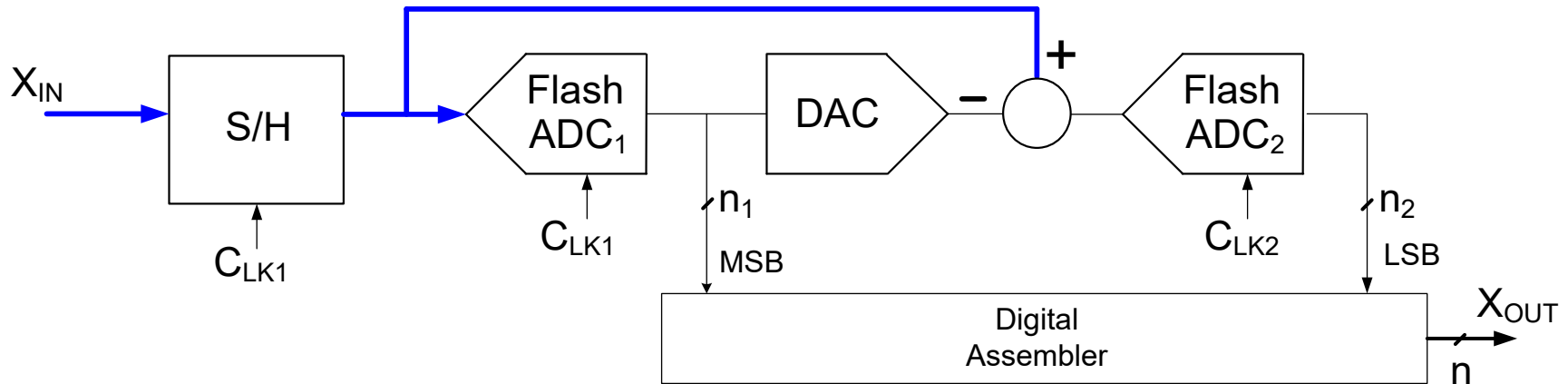
- Flash ADC has some really desirable properties (simple and fast)
- Wouldn't it be nice if we could derive most of the benefits of the FLASH ADC without the major limitations

To be practical at higher resolution, must address the major limitation of the FLASH ADC

Major Limitation of FLASH ADC at higher resolutions?

Number of comparators increases geometrically --- 2^n

Two-Step Flash ADC



Can operate asynchronously (either after first S/H or even w/o S/H)

Reduces the number of comparators significantly

Reduces complexity of thermometer to binary converter

Residue signal at input to second Flash ADC is small

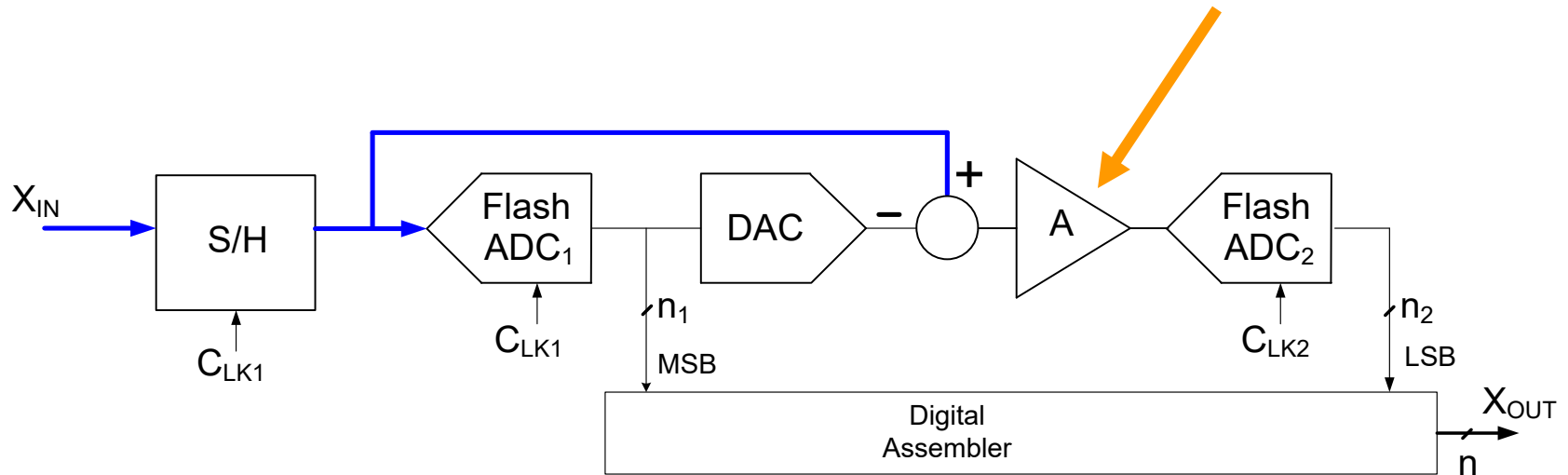
Difference block is a linear module that must be accurate

Have added a DAC that must have accuracy at the overall ADC resolution level

Speed of difference amplifier and DAC limit speed of ADC

Sequential clocking of ADC₁ and ADC₂ limits speed of ADC

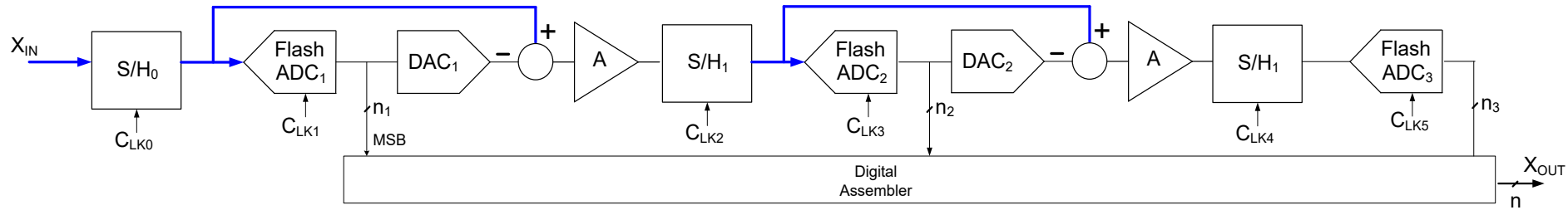
Two-Step Flash ADC with Interstage Gain



Speed of A of concern

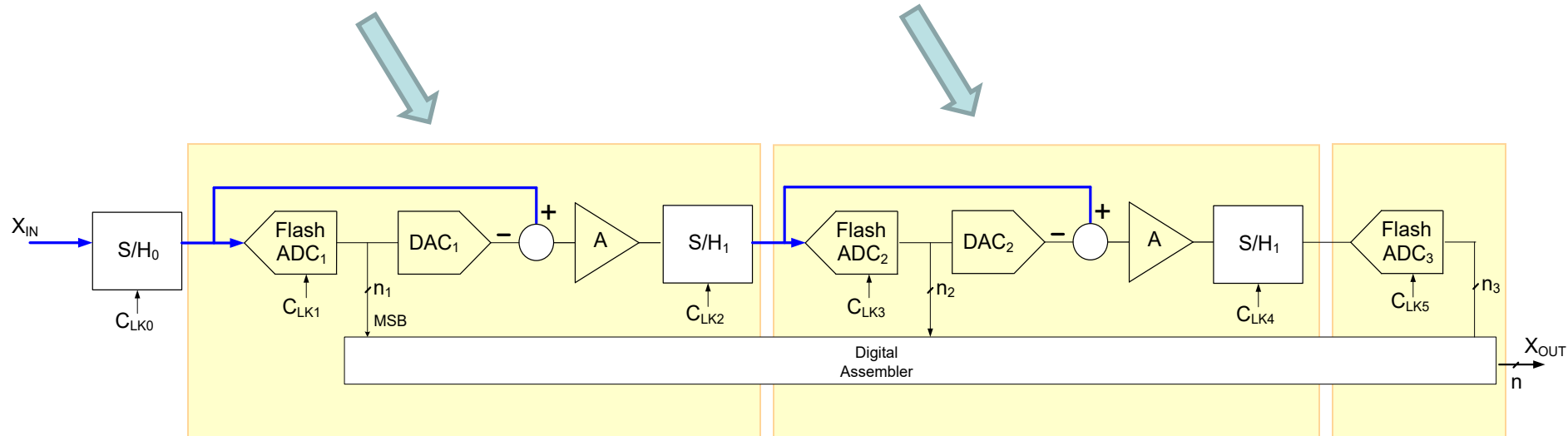
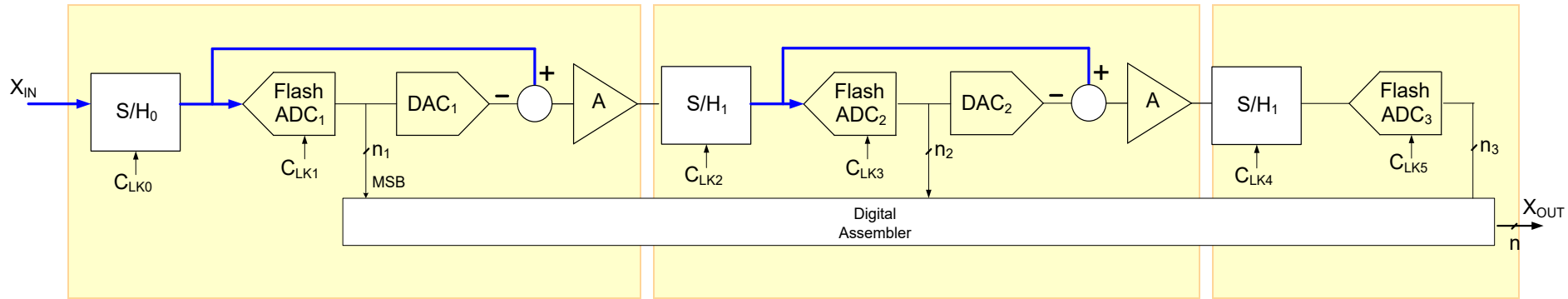
Considerable power dissipation in A amplifier

Three-Step Flash ADC with Interstage Gain and S/H



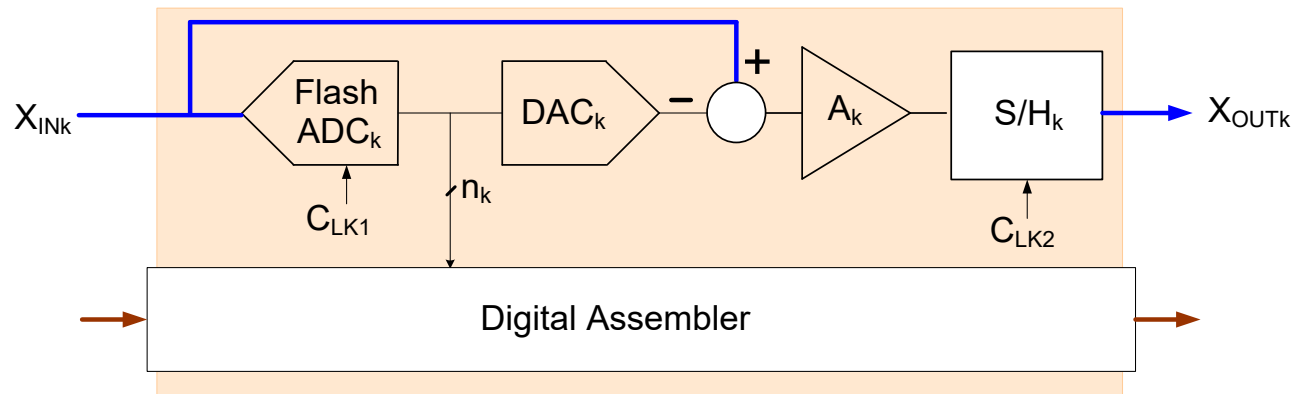
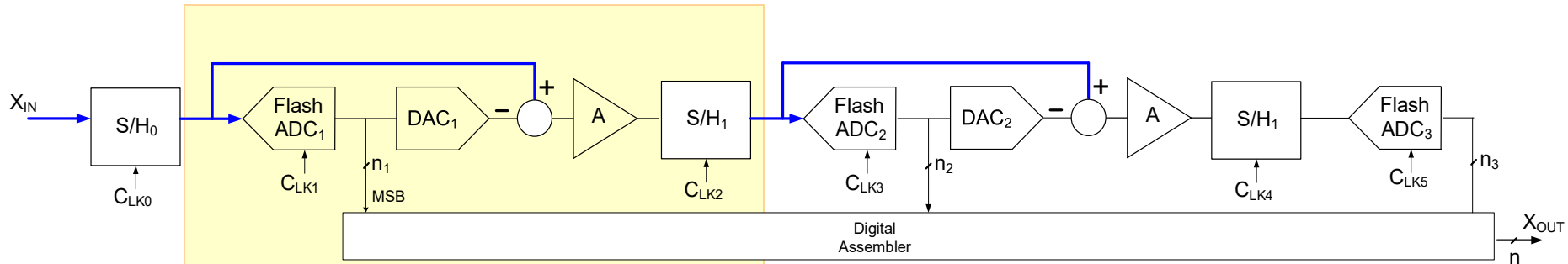
- S/H frees first stage to take another sample during second stage conversion
- This has a pipelining capability

Three-Step Flash ADC with Interstage Gain and S/H

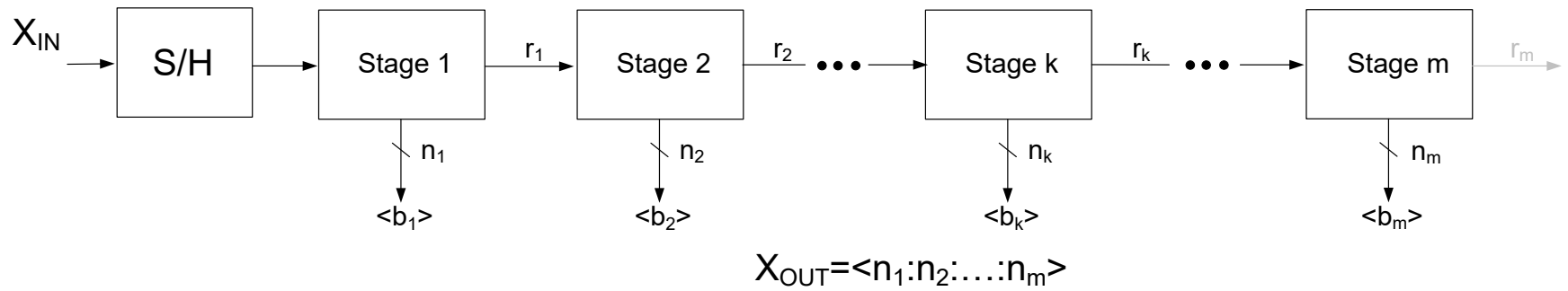


Same structure, different grouping!

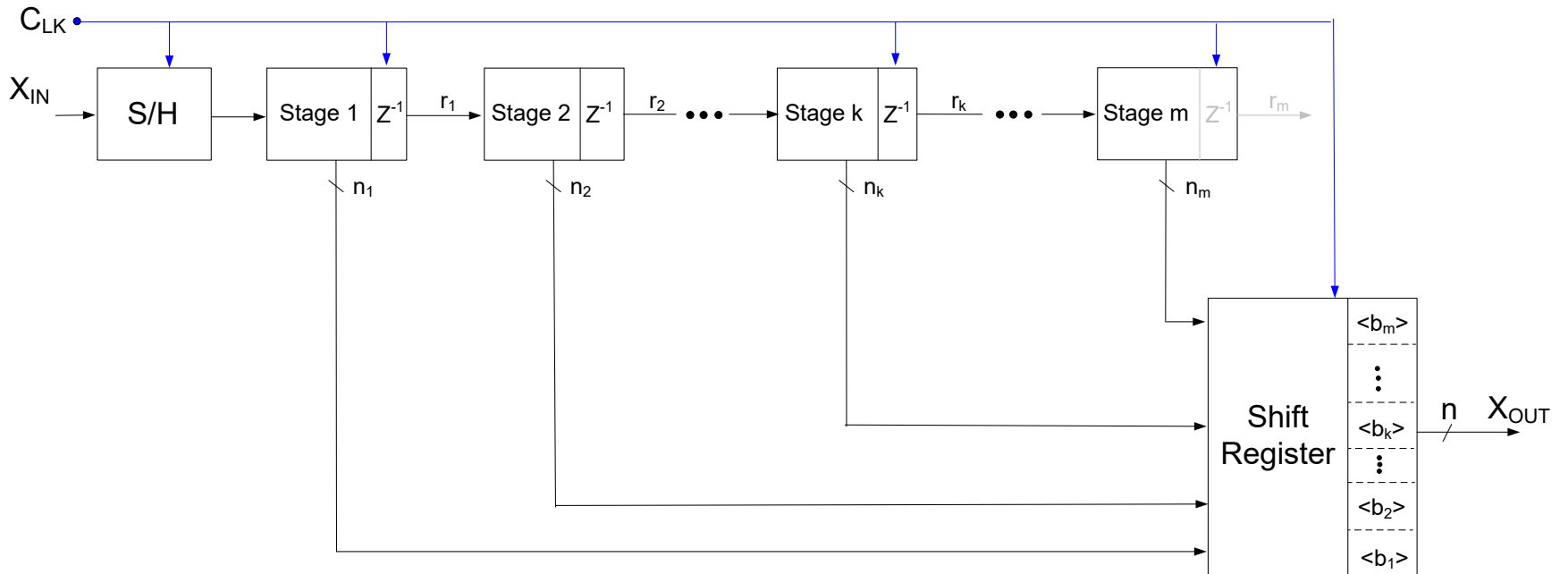
Three-Step Flash ADC with Interstage Gain



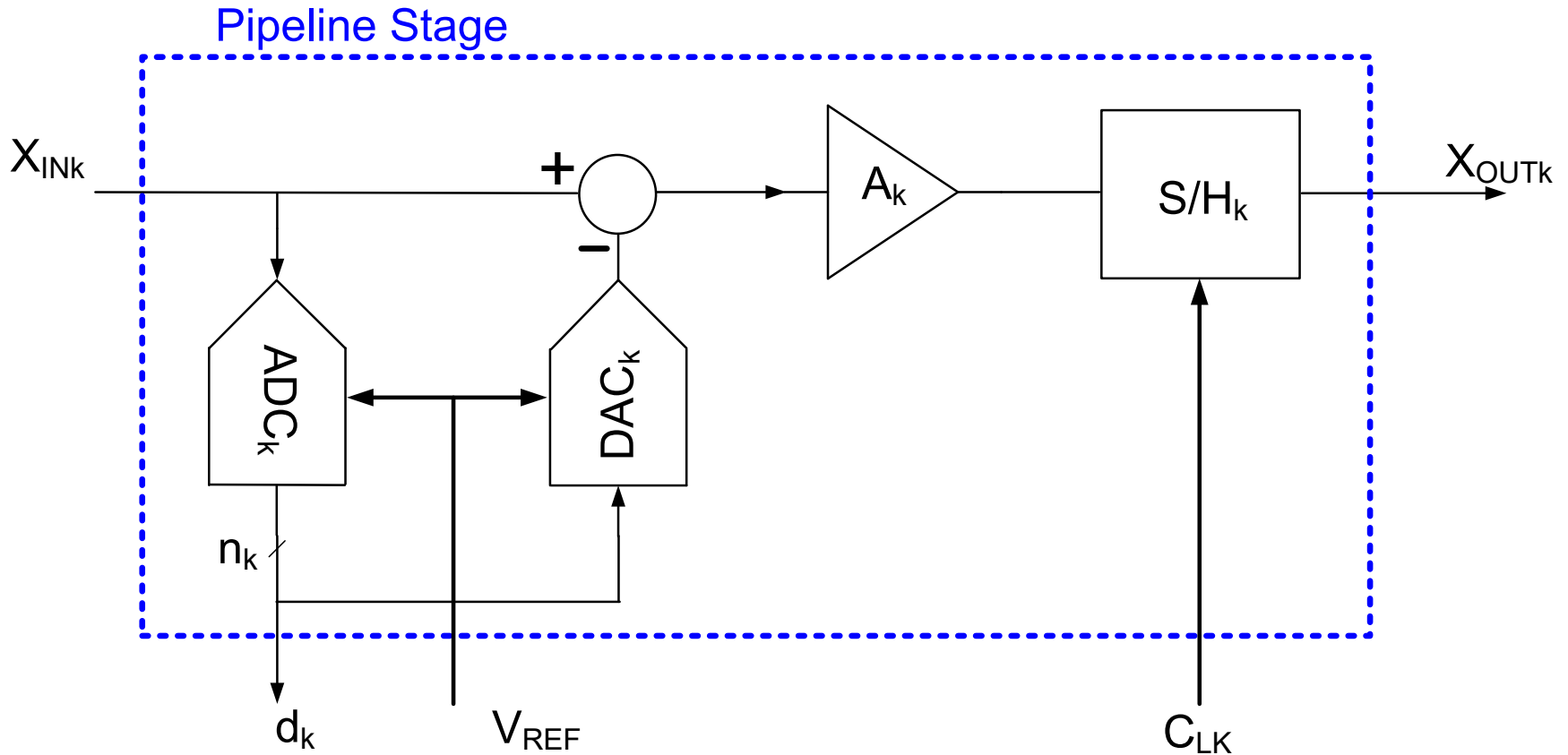
Pipelined ADC



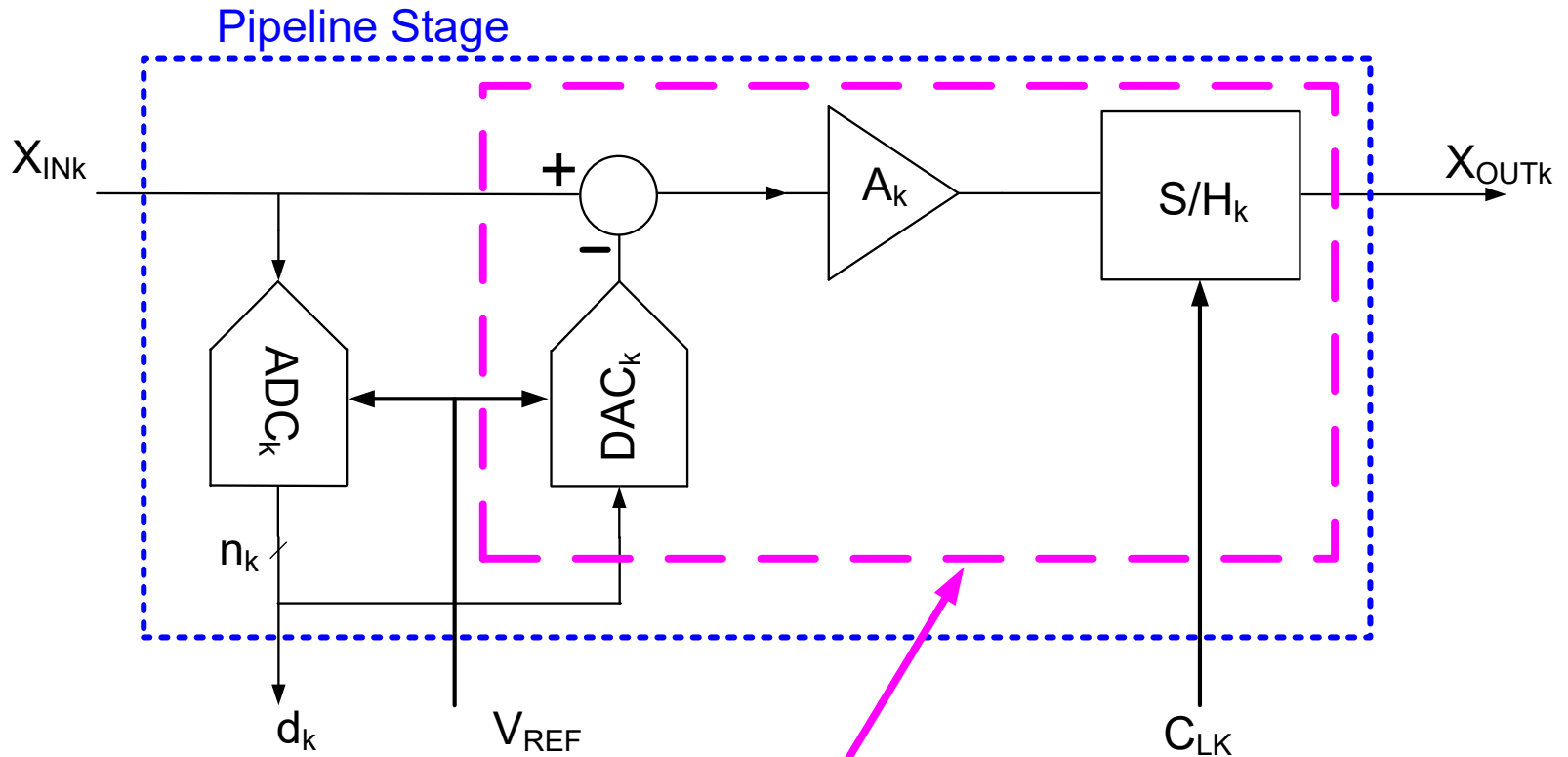
Pipelined ADC



Pipelined ADC Stage k

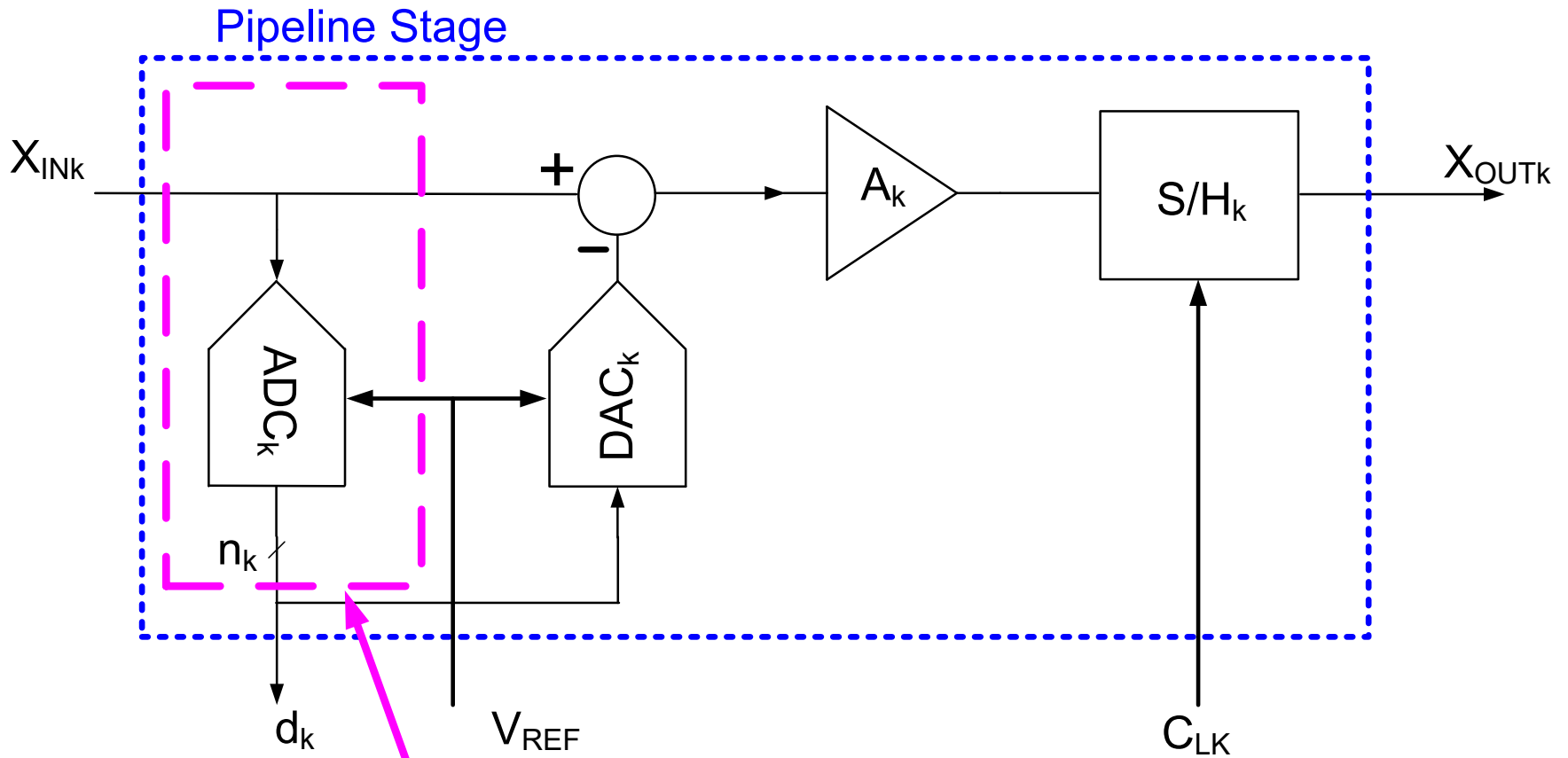


Pipelined ADC Stage k



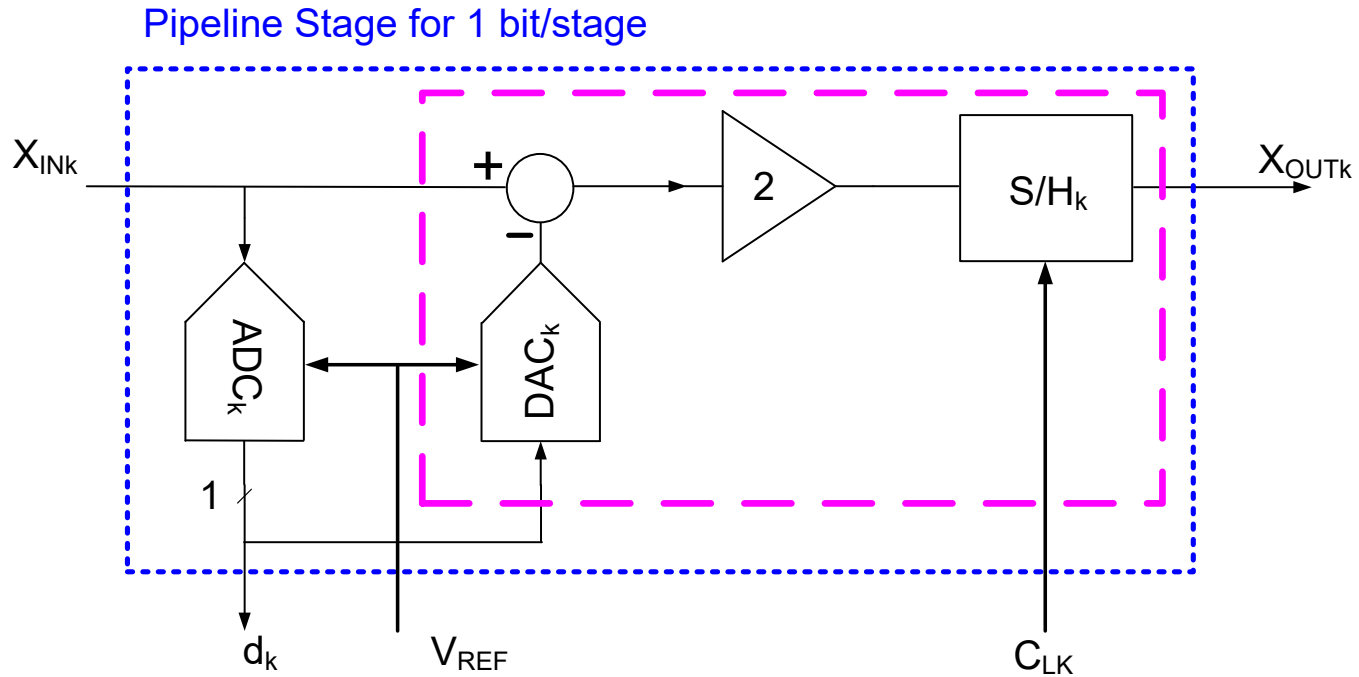
Usually Realized as
Single SC Block

Pipelined ADC Stage k



Usually Realized as Flash ADC
(often simple comparator if $n_k=1$)

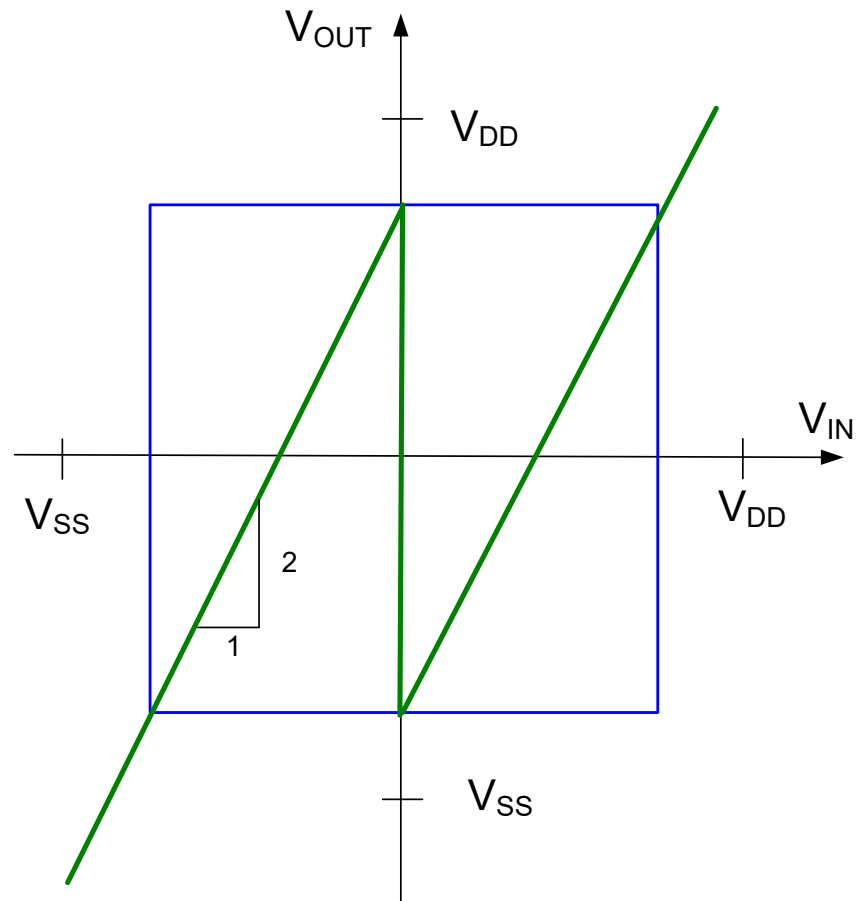
Pipelined ADC Stage k



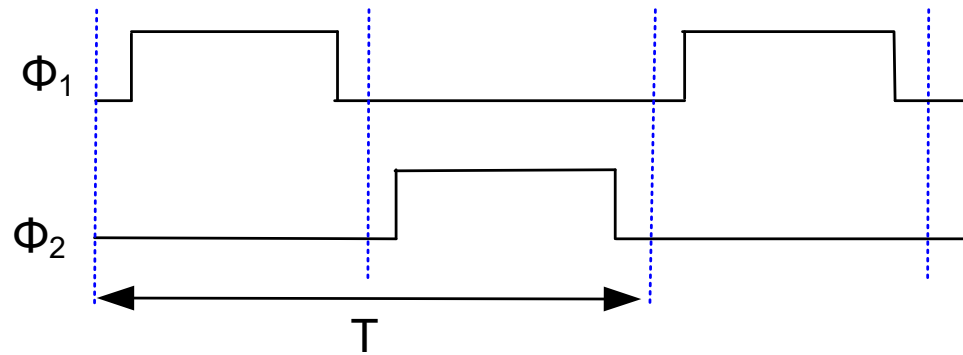
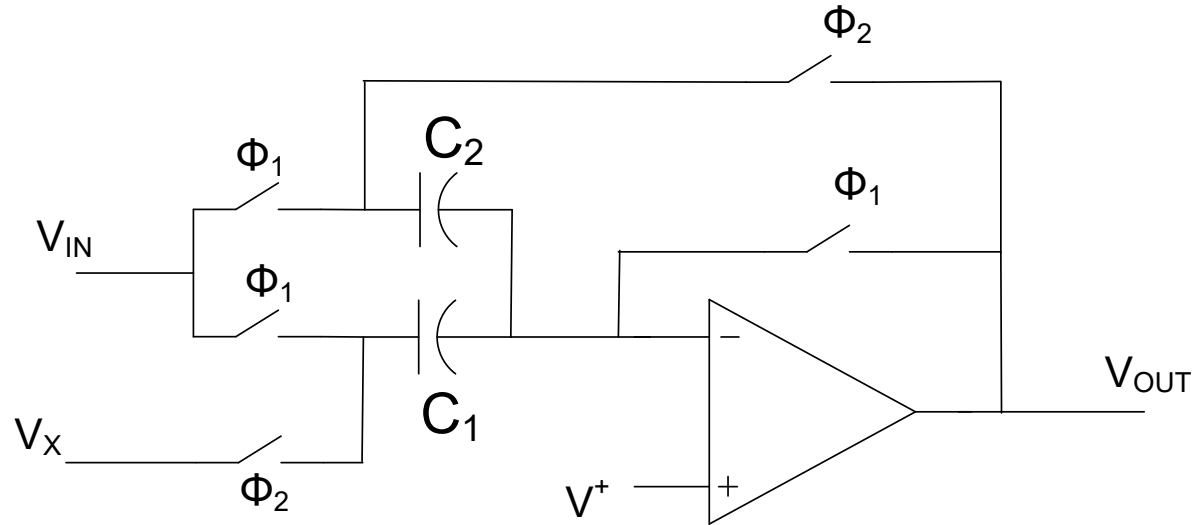
$$V_O = \begin{cases} 2V_{IN} + \frac{V_{REF}}{2} & V_{IN} < 0 \\ 2V_{IN} - \frac{V_{REF}}{2} & V_{IN} > 0 \end{cases}$$

Transfer Characteristics for 1 bit/stage

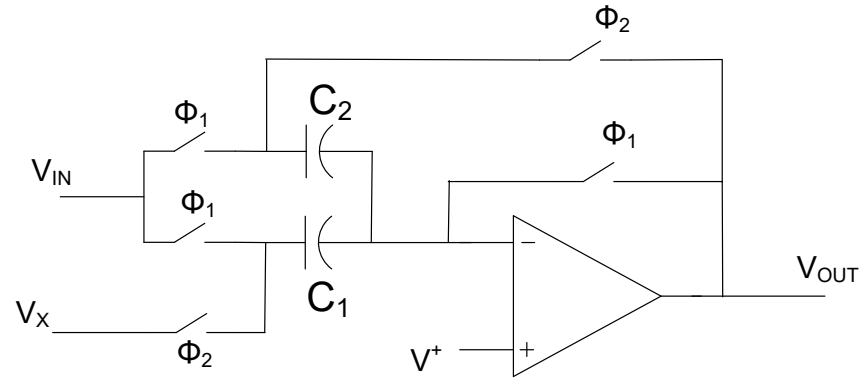
$$V_O = \begin{cases} 2V_{IN} + \frac{V_{REF}}{2} & V_{IN} < 0 \\ 2V_{IN} - \frac{V_{REF}}{2} & V_{IN} > 0 \end{cases}$$



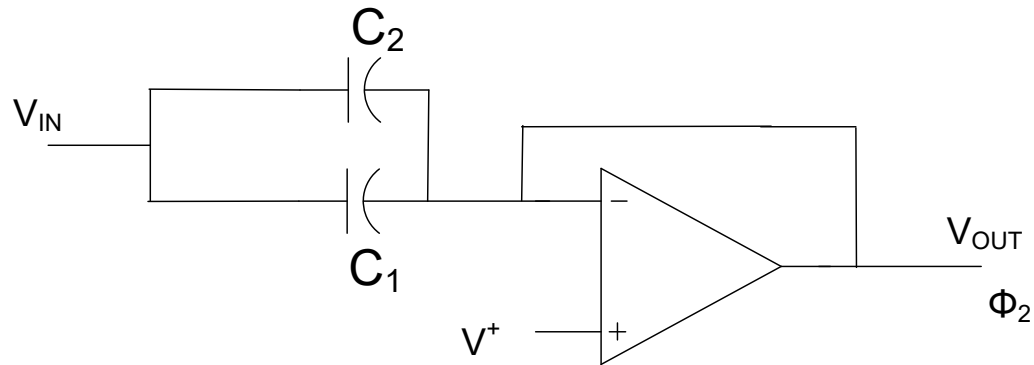
Consider the following circuit



Consider the following circuit

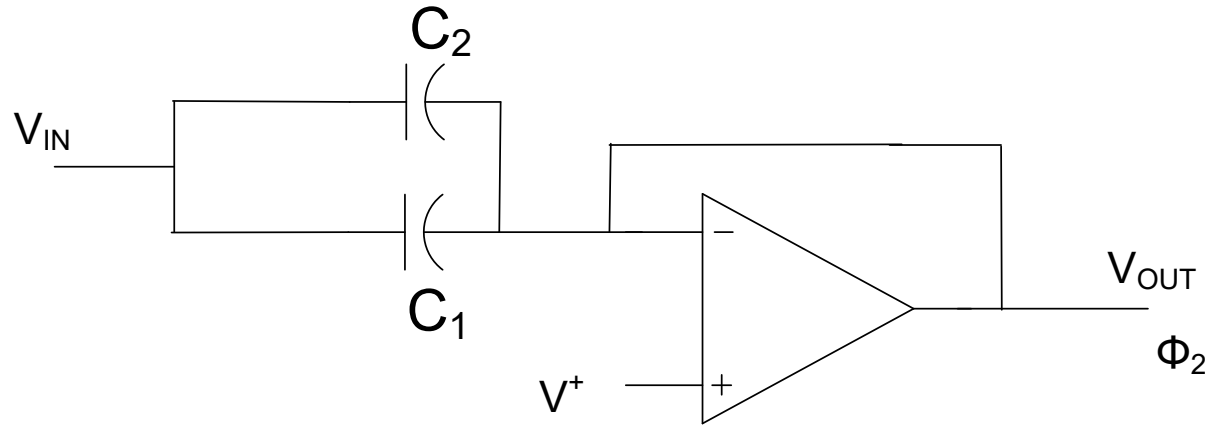


During Φ_1



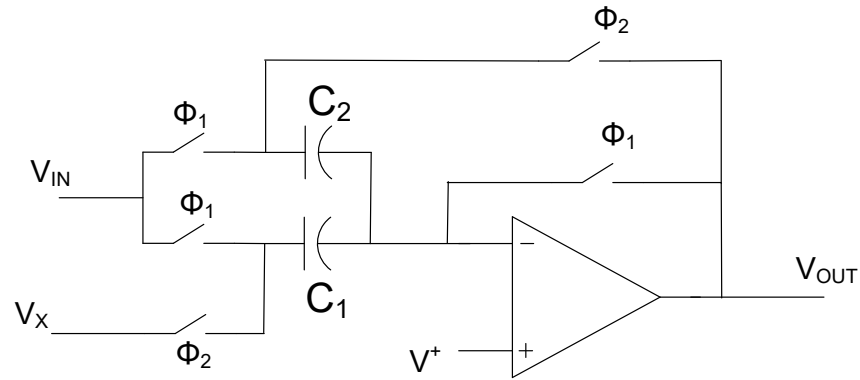
Consider the following circuit

During Φ_1

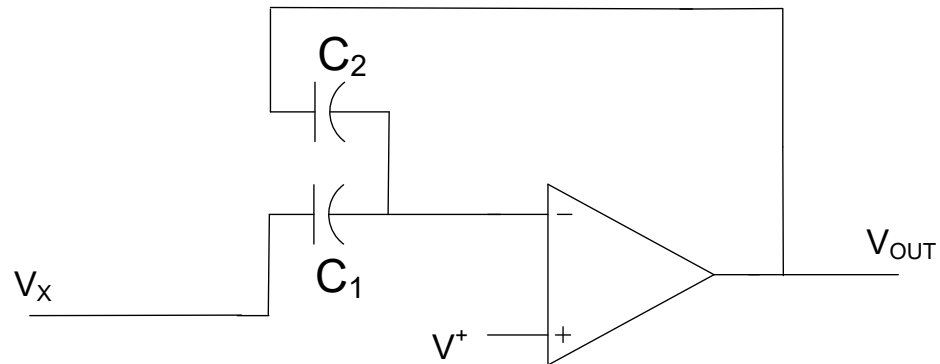


$$Q_1 = C_1 (V_{IN} - V^+)$$
$$Q_2 = C_2 (V_{IN} - V^+)$$

Consider the following circuit

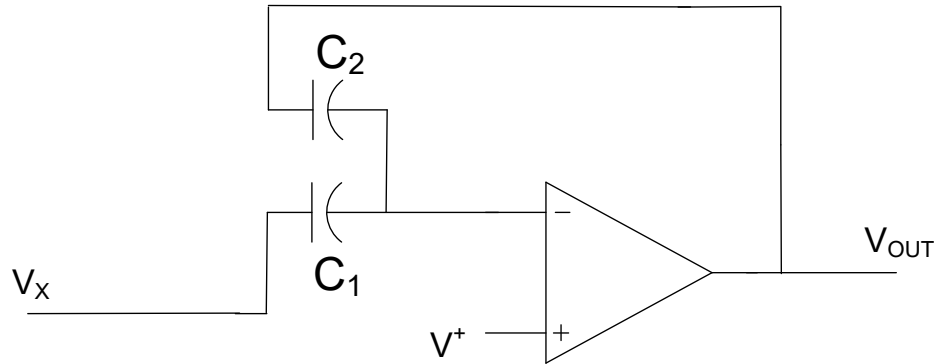


During Φ_2



Consider the following circuit

During Φ_2



$$Q_1 = C_1 (V_{\text{IN}} - V^+)$$

$$Q_2 = C_2 (V_{\text{IN}} - V^+)$$

Define Q_{1T} to be the charge transferred from C_1 during phase Φ_2

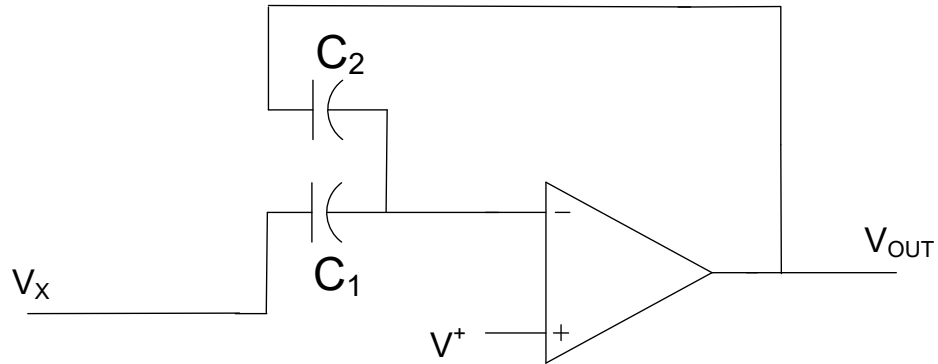
$$Q_{1T} = C_1 (V_{\text{IN}} - V^+) - C_1 (V_X - V^+) = C_1 (V_{\text{IN}} - V_X)$$

Define Q_{2F} to be the total charge on C_2 during phase Φ_2

$$Q_{2F} = Q_2 + Q_{1T} = C_2 (V_{\text{IN}} - V^+) + C_1 (V_{\text{IN}} - V_X) = (C_1 + C_2) V_{\text{IN}} - C_2 V^+ - C_1 V_X$$

Consider the following circuit

During Φ_2

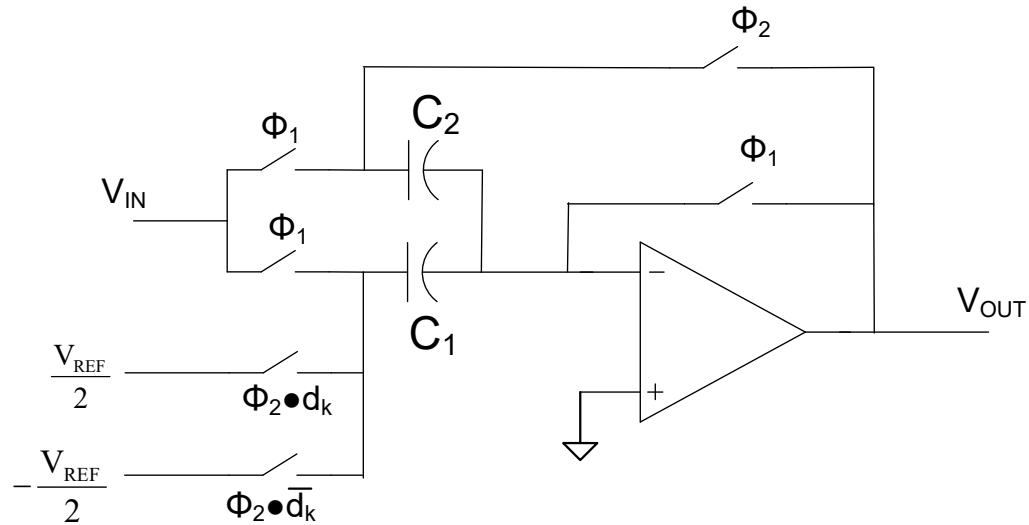


$$Q_{2F} = (C_1 + C_2)V_{IN} - C_2V^+ - C_1V_X$$

$$V_{C2F} = \frac{Q_{2F}}{C_2} = \left(1 + \frac{C_1}{C_2}\right)V_{IN} - V^+ - \frac{C_1}{C_2}V_X$$

$$V_{OUTF} = V_{C2F} + V^+ = \left(1 + \frac{C_1}{C_2}\right)V_{IN} - \frac{C_1}{C_2}V_X$$

Consider the following circuit

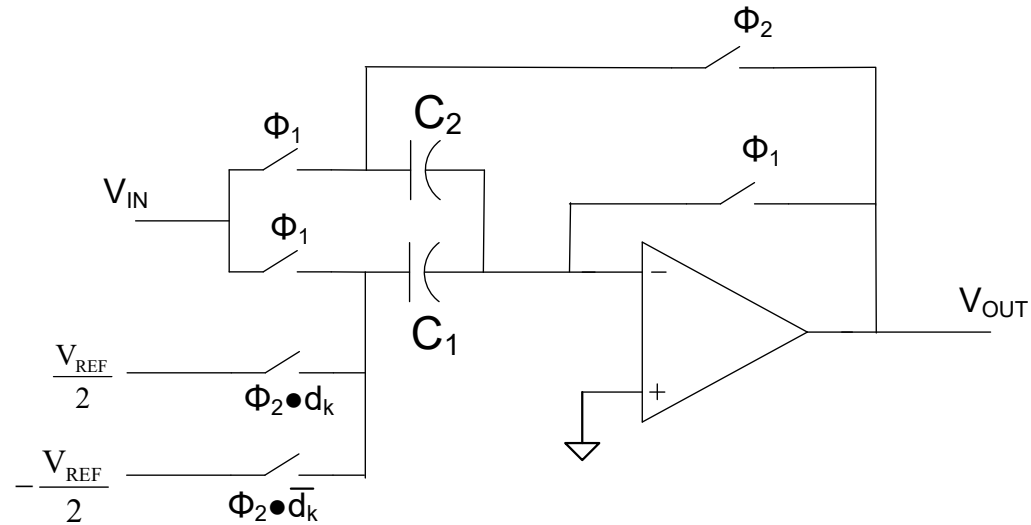


$$V_{OUTF} = \left(1 + \frac{C_1}{C_2}\right) V_{IN} - \frac{C_1}{C_2} V_X$$

If $C_1 = C_2 = C$ and $V_X = -\frac{V_{REF}}{2}$

$$V_{OUTF} = 2V_{IN} + \frac{V_{REF}}{2}$$

Consider the following circuit



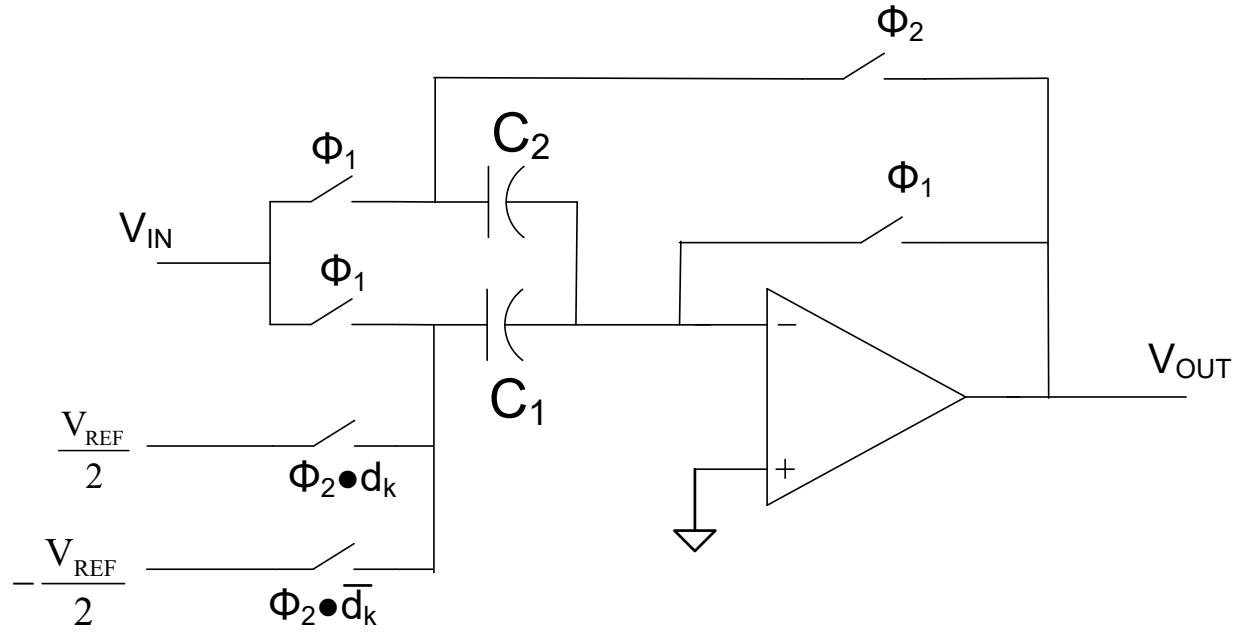
$$V_{OUTF} = \left(1 + \frac{C_1}{C_2}\right) V_{IN} - \frac{C_1}{C_2} V_X$$

Likewise

$$\text{If } C_1 = C_2 = C \text{ and } V_X = \frac{V_{REF}}{2}$$

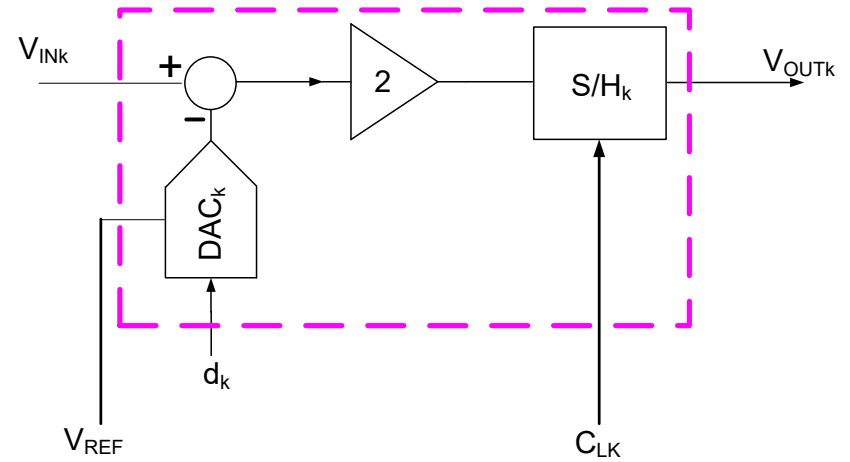
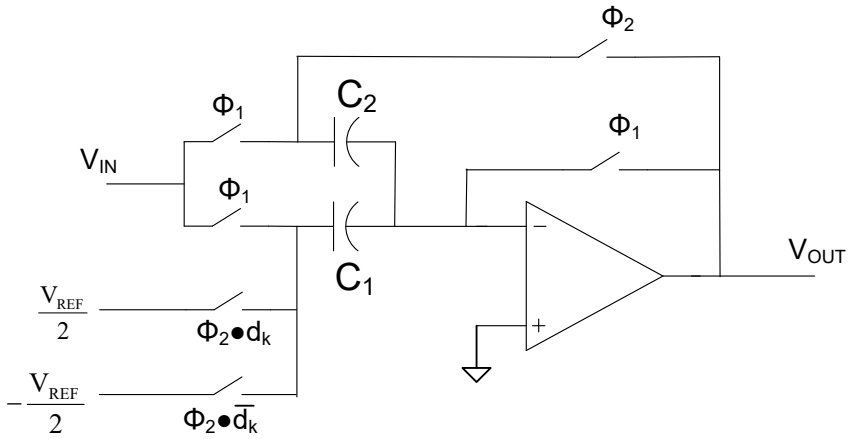
$$V_{OUTF} = 2V_{IN} - \frac{V_{REF}}{2}$$

Observe



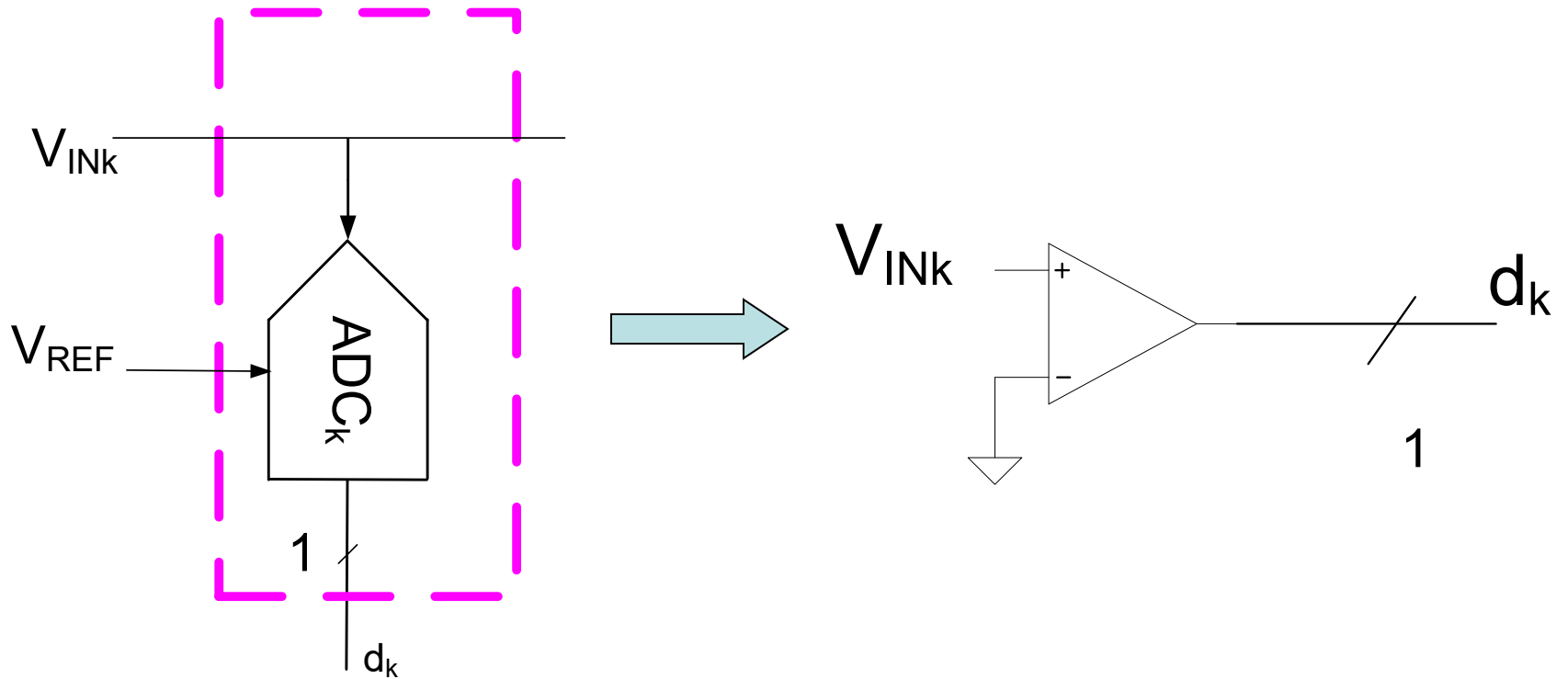
$$V_O = \begin{cases} 2V_{IN} + \frac{V_{REF}}{2} & V_{IN} < 0 \\ 2V_{IN} - \frac{V_{REF}}{2} & V_{IN} > 0 \end{cases}$$

1-bit/Stage Pipeline Implementation

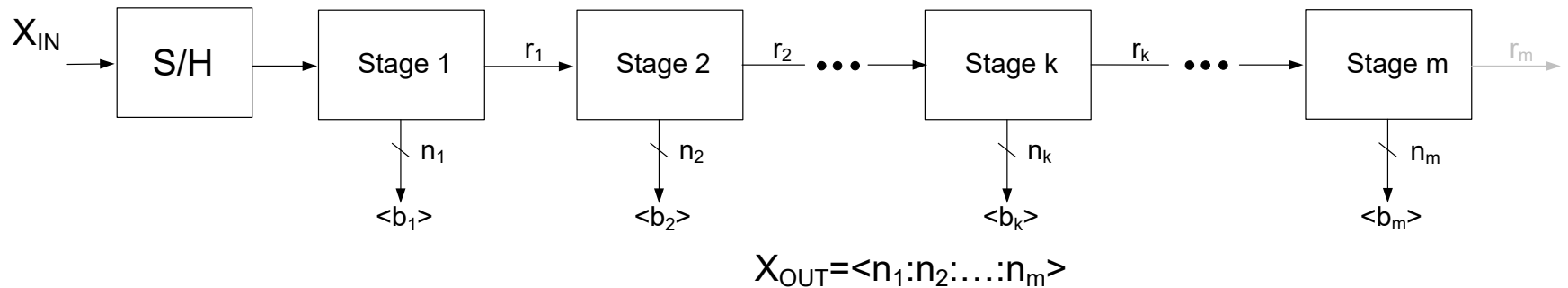


$$V_O = \begin{cases} 2V_{IN} + \frac{V_{REF}}{2} & V_{IN} < 0 \\ 2V_{IN} - \frac{V_{REF}}{2} & V_{IN} > 0 \end{cases}$$

1-bit/Stage Pipeline Implementation



Pipelined ADC



- Pipelined structure is widely used
- More than one bit/stage is often used
- Optimal number of bits/stage still an area of debate
- Conceptually can simply design one stage and then copy/paste to increase resolution
- Accuracy (and correspondingly power) in latter stages dramatically reduced
- Most power consumed in op amps
- Power dominantly allocated to S/H and MSB stages

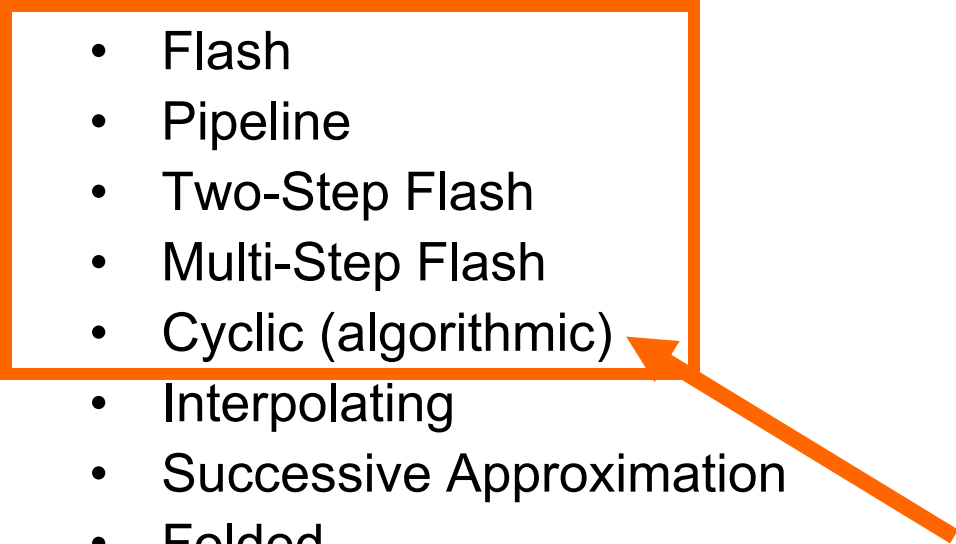


Stay Safe and Stay Healthy !

End of Lecture 37

ADC Types

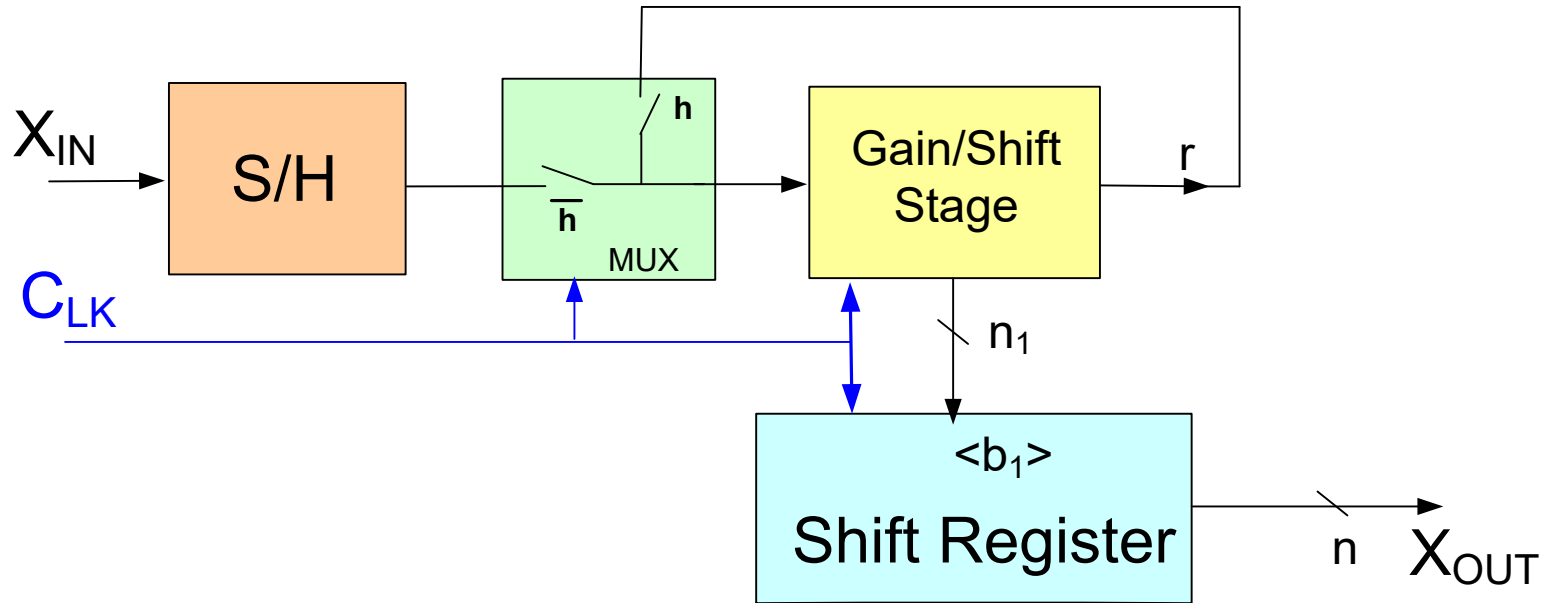
Nyquist Rate

- Flash
 - Pipeline
 - Two-Step Flash
 - Multi-Step Flash
 - Cyclic (algorithmic)
 - Interpolating
 - Successive Approximation
 - Folded
 - Dual Slope
- 

Over-Sampled

- Single-bit
- Multi-bit
- First-order
- Higher-order
- Continuous-time

Cyclic (Algorithmic) ADC



- Re-use Pipelined Stage
- Small amount of hardware
- Effective thru-put decreases

ADC Types

Nyquist Rate

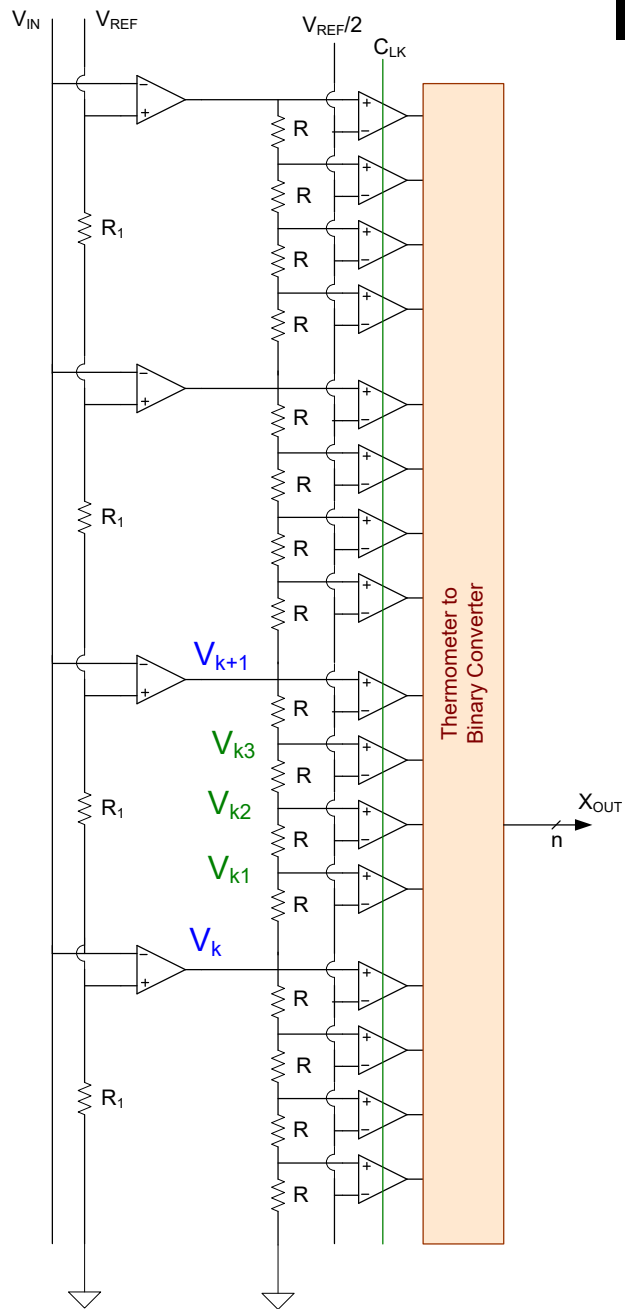
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Over-Sampled

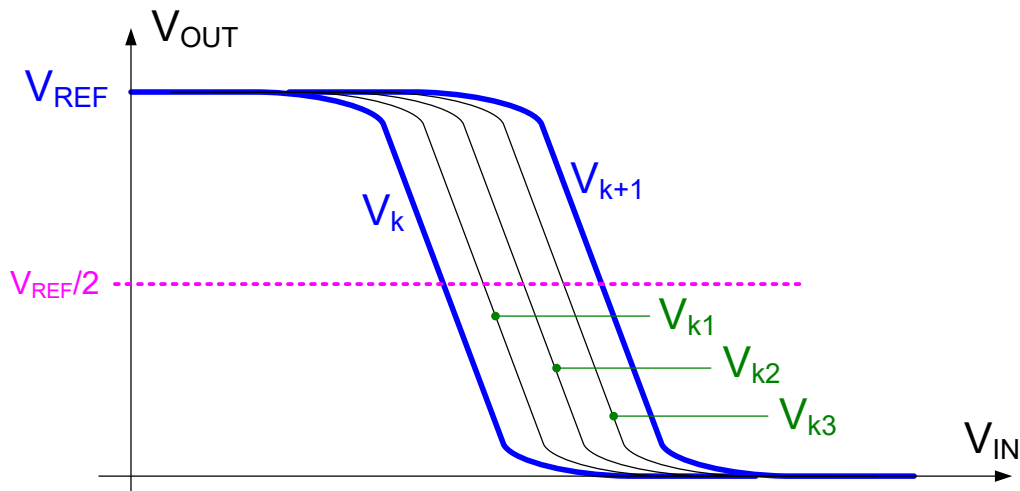
- Single-bit
- Multi-bit
- First-order
- Higher-order
- Continuous-time



Interpolating ADC



- Amplifiers are finite-gain saturating
- Shown for 4-bit
- Clocked comparators usually regenerative
- Reduces Offset Requirements for Comparators



ADC Types

Nyquist Rate

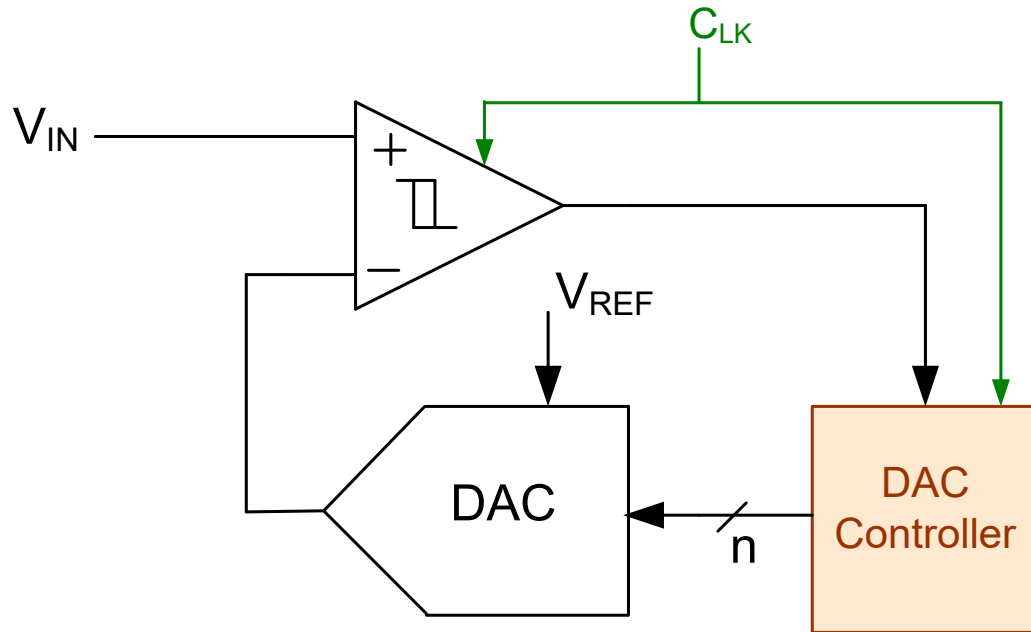
- Flash
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- Successive Approximation
- Folded
- Dual Slope

Over-Sampled

- Single-bit
- Multi-bit
- First-order
- Higher-order
- Continuous-time



SAR ADC



- DAC Controller may be simply U/D counter
- Binary search controlled by Finite State Machine is faster
- SAR ADC will have no missing codes if DAC is monotone
- Not very fast but can be small

ADC Types

Nyquist Rate

- Flash
- Pipeline
- Two-Step Flash
- Multi-Step Flash
- Cyclic (algorithmic)
- Interpolating
- Successive Approximation
- Folded
- Dual Slope

Over-Sampled

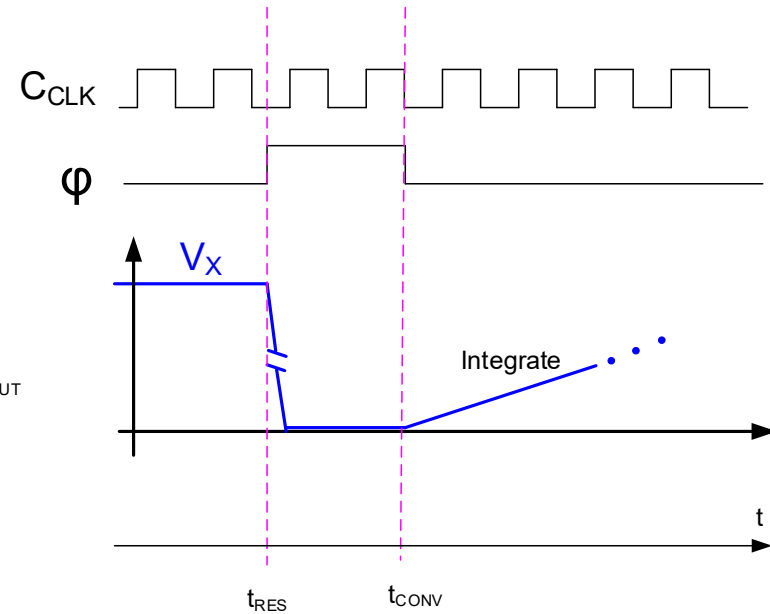
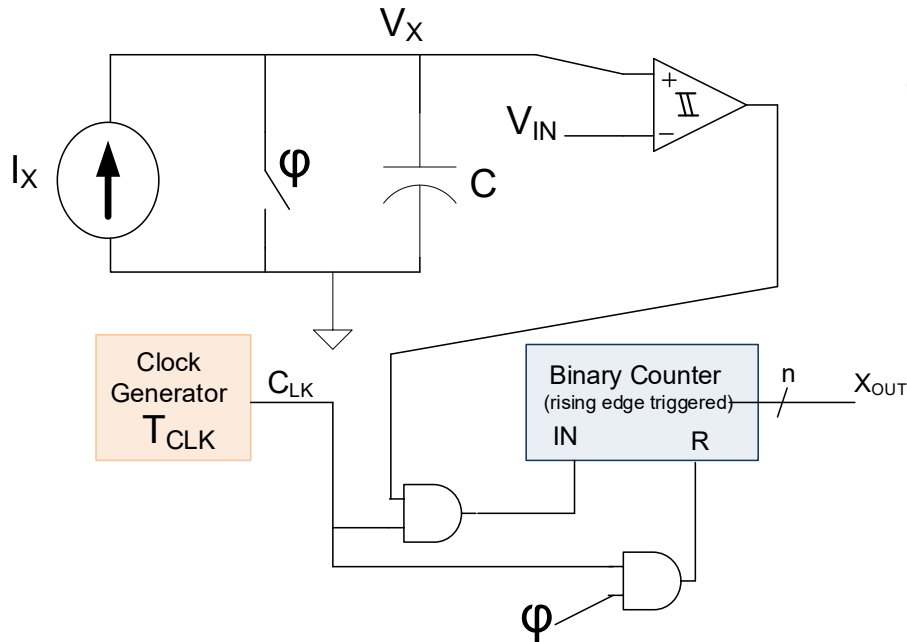
- Single-bit
- Multi-bit
- First-order
- Higher-order
- Continuous-time

And Single Slope



Single-Slope ADC

Sometimes Termed Integrating ADC



Falling edge of ϕ synchronous with respect to falling edge of C_{CLK}

Can convert asynchronously wrt C_{CLK} or can be a clocked ADC where conversion clock signal is synchronous wrt C_{CLK} .

Output valid when comparator output goes low

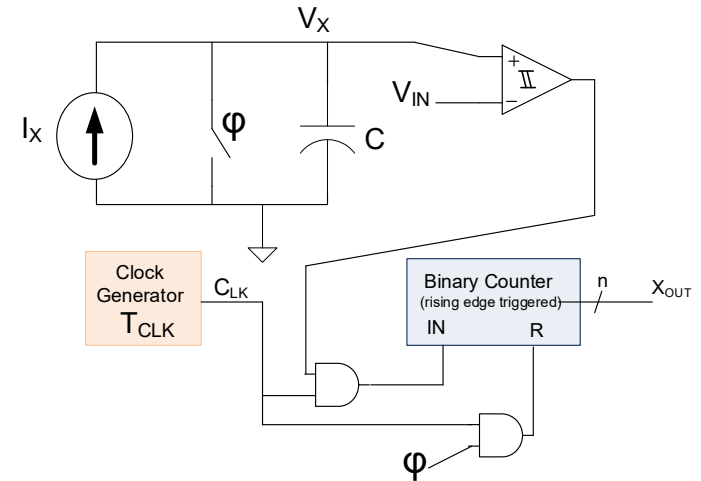
Note V_{REF} not explicitly shown in ADC architecture

Single-Slope ADC

Operation:

Assume $V_X(t_{\text{CONV}})=0$

$$V_X(t) = \frac{1}{C} \int_{t_{\text{CONV}}}^t I_X dt = \frac{I_X}{C} (t - t_{\text{CONV}}) \quad (1)$$



Assume $I_X, V_{\text{REF}}, R, C, T_{\text{CLK}}$ are selected to satisfy the relationship

$$V_{\text{REF}} = \frac{1}{C} \int_{t_{\text{CONV}}}^{t_{\text{CONV}} + 2^n T_{\text{CLK}}} I_X dt = \frac{I_X}{C} 2^n T_{\text{CLK}} \quad \text{thus} \quad V_{\text{LSB}} = \frac{V_{\text{REF}}}{2^n} = \frac{I_X}{C} T_{\text{CLK}} \quad (2)$$

Comparator will stop counter when $V_X = V_{\text{IN}}$ and counter output will be $X_{\text{OUT}} = k$

$$\text{thus } V_X(t_{\text{CONV}} + kT_{\text{CLK}}) = V_{\text{IN}} + \varepsilon \quad \text{where } 0 < \varepsilon < V_{\text{LSB}}$$

It follows from (1) that

$$V_X(t_{\text{CONV}} + kT_{\text{CLK}}) = \frac{I_X}{C} kT_{\text{CLK}} = V_{\text{IN}} + \varepsilon \quad (3)$$

And finally from (2) and (3) that

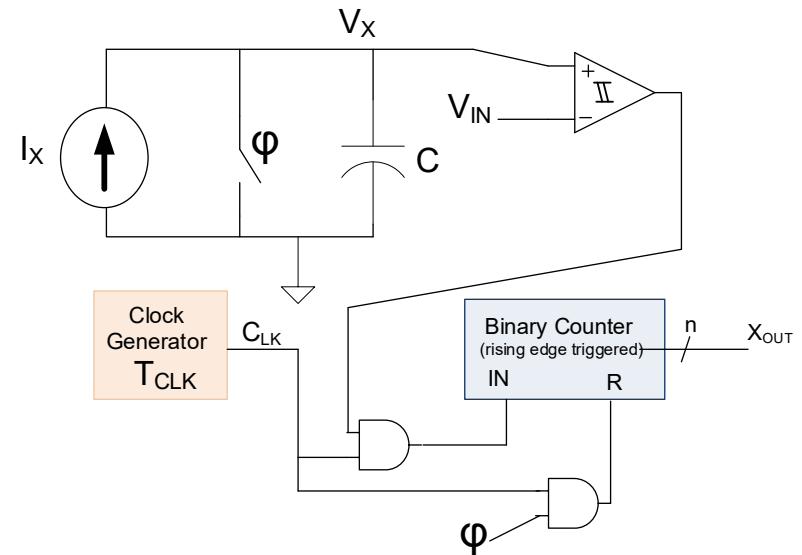
$$V_{\text{IN}} = k \left(\frac{I_X}{C} T_{\text{CLK}} \right) - \varepsilon \cong \frac{k}{2^n} V_{\text{REF}}$$

Single-Slope ADC

$I_X, V_{REF}, R, C, T_{CLK}$ must satisfy the relationship

$$V_{REF} = \frac{I_X}{C} 2^n T_{CLK} \quad (1)$$

$$V_{IN} \cong \frac{k}{2^n} V_{REF}$$



Benefits: Very simple structure and can provide a low-cost easy solution for low speed applications

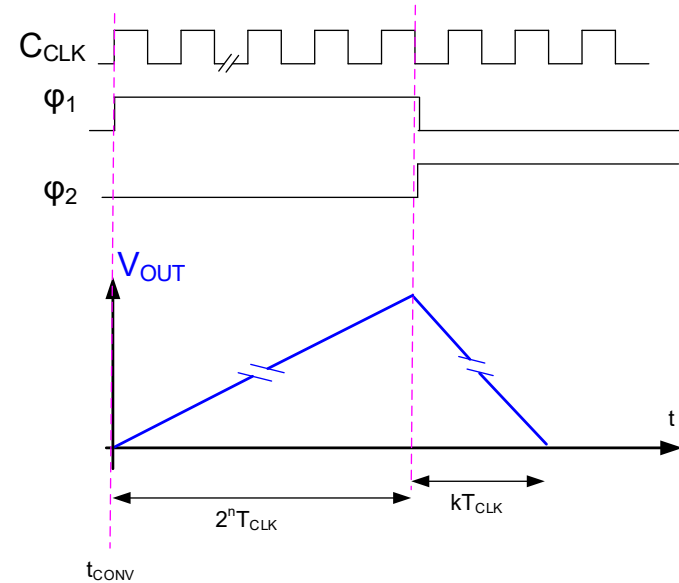
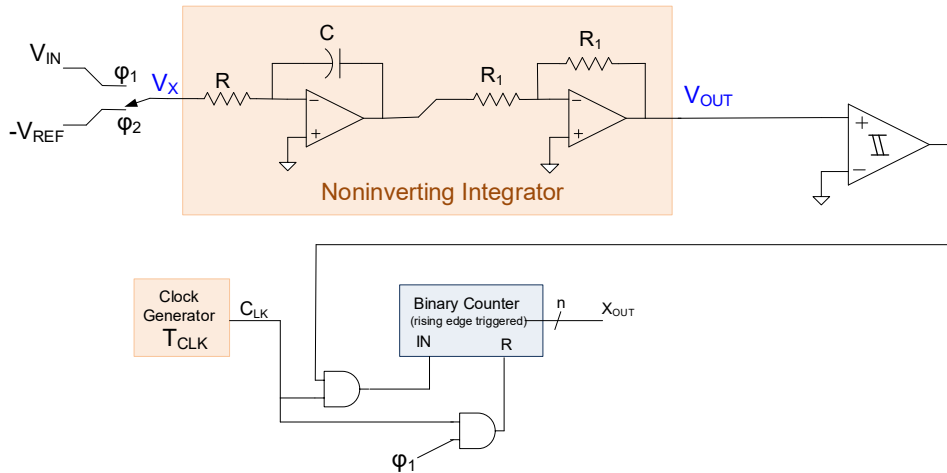
Limitations:

- Process variations make it difficult to satisfy (1)
- C is large and must be off chip
- Linearity of C important (since off-chip)
- Nonlinearity in I_X degrades performance
- R_{OUT} of I_X degrades performance
- Slow
- Not widely used

Options for improving performance:

- Introduce self-calibration cycle to satisfy (1) by trimming I_X or C
- Use high-impedance current source
- Use OP-Amp Based RC integrator

Dual-Slope ADC



- Output valid when comparator output transitions to Low
- Must set RC time constants and CCLK so output does not saturate
- Shown as noninverting integrator but slight modification will also work with inverting integrator
- Other integrator structures could be used
- Can leave one or more clock cycles between integrate up and integrate down

Dual-Slope ADC

Operation:

$$V_{OUT}(t) = \frac{1}{RC} \int_{t_{CONV}}^t V_X dt$$

During ϕ_1 , integrate V_{IN} for time $2^n T_{CLK}$

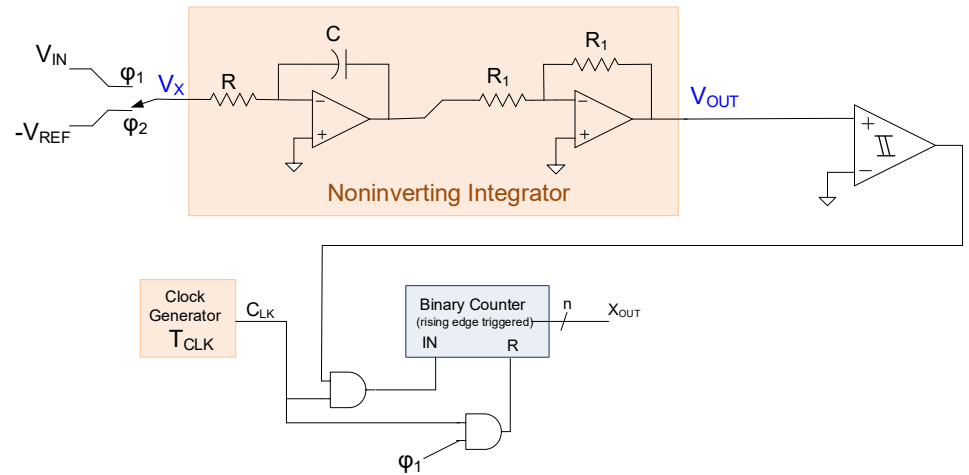
At end of integrate up interval, $V_{OUT}(2^n T_{CLK}) = \frac{1}{RC} V_{IN} 2^n T_{CLK}$

Reset counter at time $2^n T_{CLK}$

During ϕ_2 , integrate $-V_{IN}$ until comparator goes low and count clock transitions during down integration interval. At time comparator changes states, $V_{OUT}=0$ and code in counter is k

$$0 = \frac{1}{RC} \int_{t_{CONV}}^{t_{CONV} + 2^n T_{CLK}} V_{IN} dt - \frac{1}{RC} \int_{t_{CONV} + 2^n T_{CLK}}^{t_{CONV} + 2^n T_{CLK} + k T_{CLK}} V_{REF} dt \quad \Rightarrow \quad \frac{1}{RC} V_{IN} 2^n T_{CLK} = \frac{1}{RC} V_{REF} k T_{CLK}$$

Solving, obtain: $V_{IN} = \frac{k}{2^n} V_{REF}$



Dual-Slope ADC

$$V_{IN} = \frac{k}{2^n} V_{REF}$$

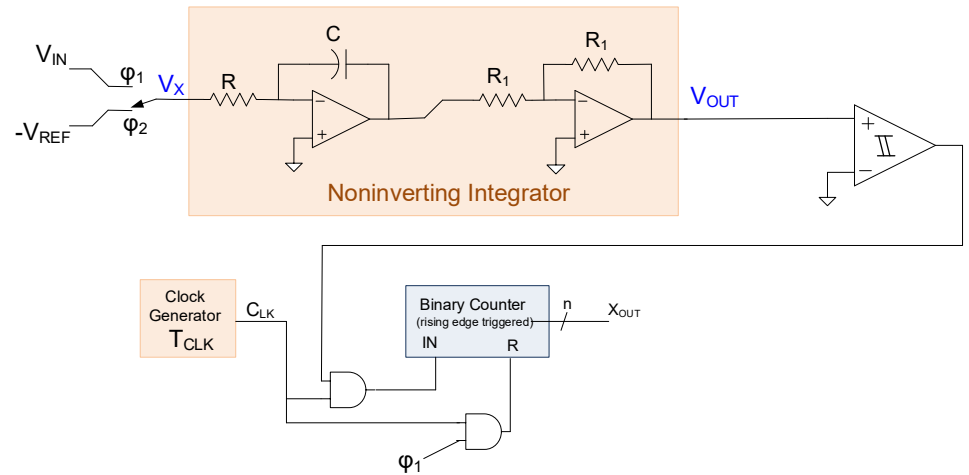
Observations:

Benefits

- Not dependent upon R, C, or T_{CLK} (provided integrator does not saturate)
- Very simple structure that can give good results and cost can be low
- Inherently monotone

Limitations:

- Capacitor large and likely must be off-chip
- Linearity of capacitor is important (particularly of concern when off-chip)
- Slow
- Not widely used





Stay Safe and Stay Healthy !

End of Lecture 37